

SiPM detectors for the LHCb SciFi tracker

Swiss Physical Society annual meeting 2019

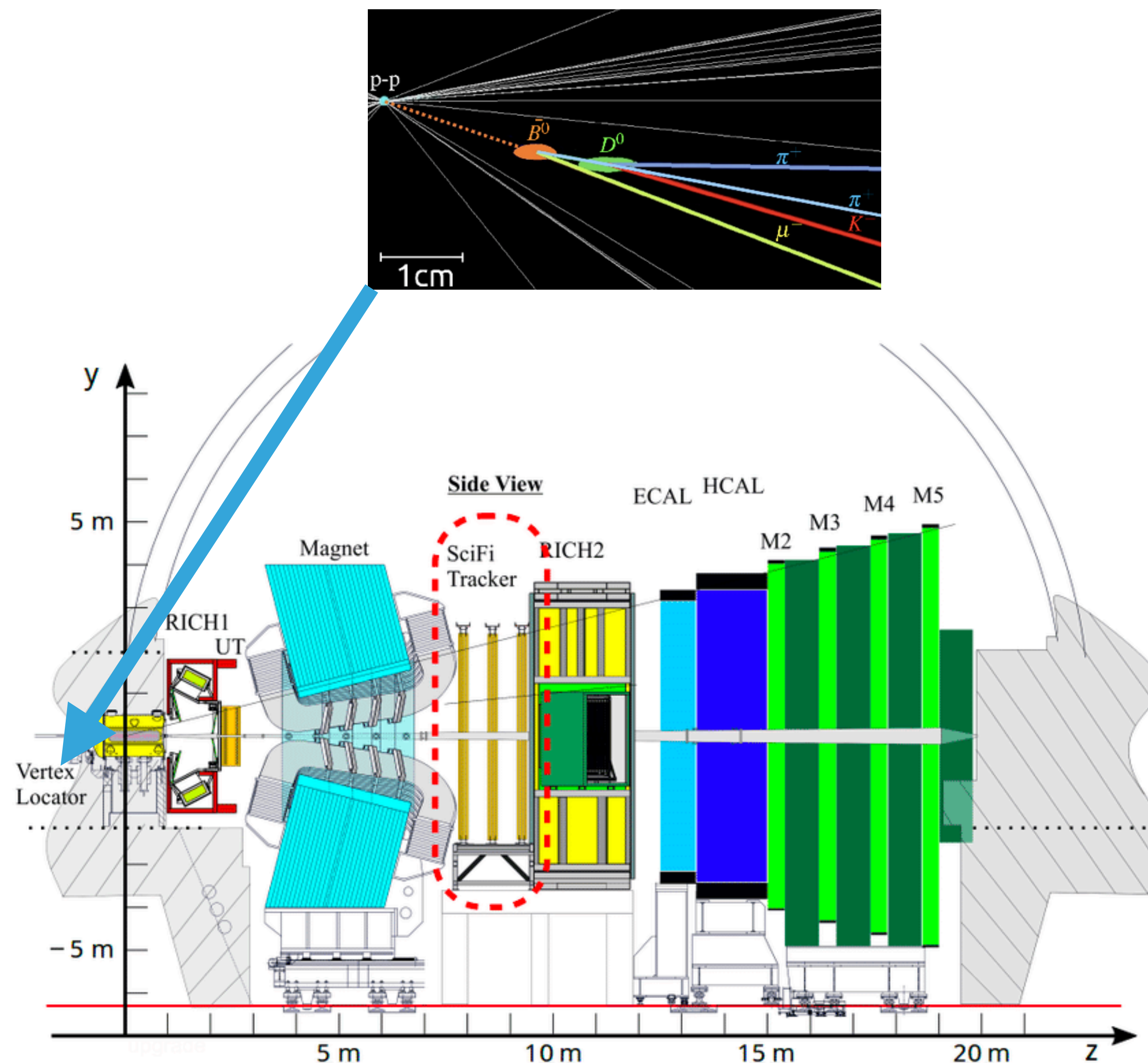
Zürich, 27/08/2019

Sebastian Schulte

The LHCb experiment

- Asymmetric forward spectrometer ($2 < \eta < 5$)
- Designed for b and c physics

- Vertex Locator:
excellent secondary vertices detection
- RICH 1 & 2 :
very good particle identification
- Tracker:
tracking of charged particles
- Calorimeter system:
detection of electrons, photons and hadrons
- Muon chambers:
tracking of muons

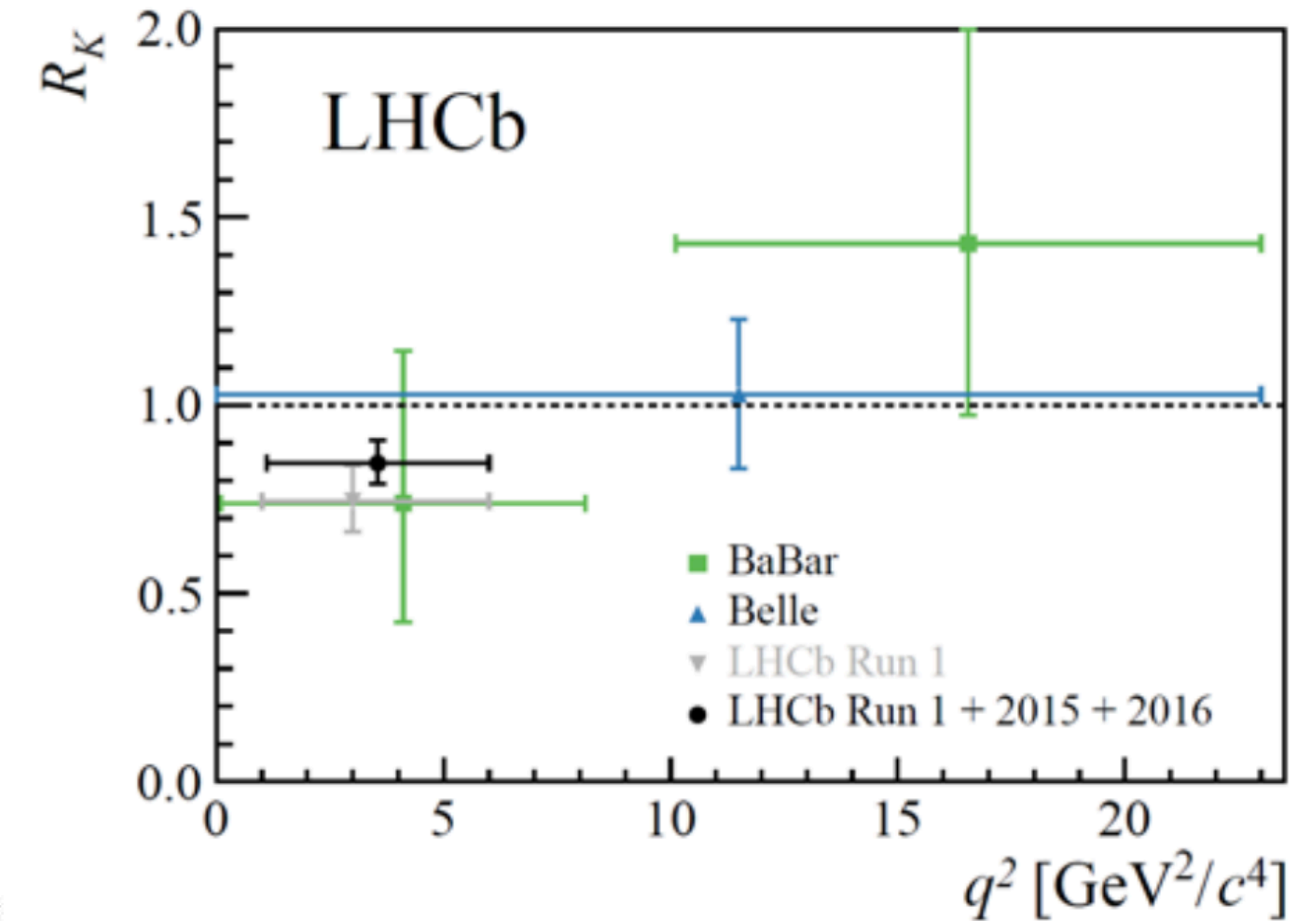


● **Outstanding results from LHCb data:**

- ▶ Observation of the Pentaquark states [Phys. Rev.Lett. 115 (2015) 072001]
- ▶ Observation of CP violation in charm decays [Phys. Rev. Lett. 122 (2019) 211803]
- ▶ Observation of the rare decay $B_s \rightarrow \mu^\pm \mu^\mp$ [Nature 522 (2015) 68-72]

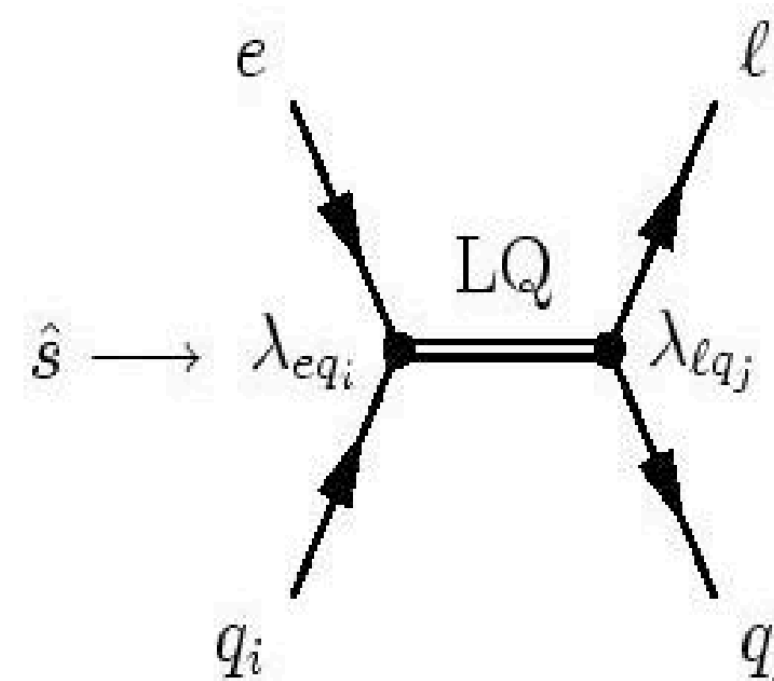
● **Interesting results in lepton flavour universality (LFU) tests:**

- ▶ Weak coupling of leptons is assumed to be universal
- ▶ New scenarios opened by recent hints of LFU anomalies [LHCb collaboration, Phys.Rev.Lett.122, 191801]



$$R_K = \frac{\mathcal{B}(B \rightarrow K\mu^+\mu^-)}{\mathcal{B}(B \rightarrow Ke^+e^-)}$$

$$0.01 \left(\frac{1 - R_K}{0.23} \right)^2 \sim \frac{\mathcal{B}(B_s \rightarrow \mu^+e^-)}{\mathcal{B}(B_s \rightarrow \mu^+\mu^-)_{SM}}$$



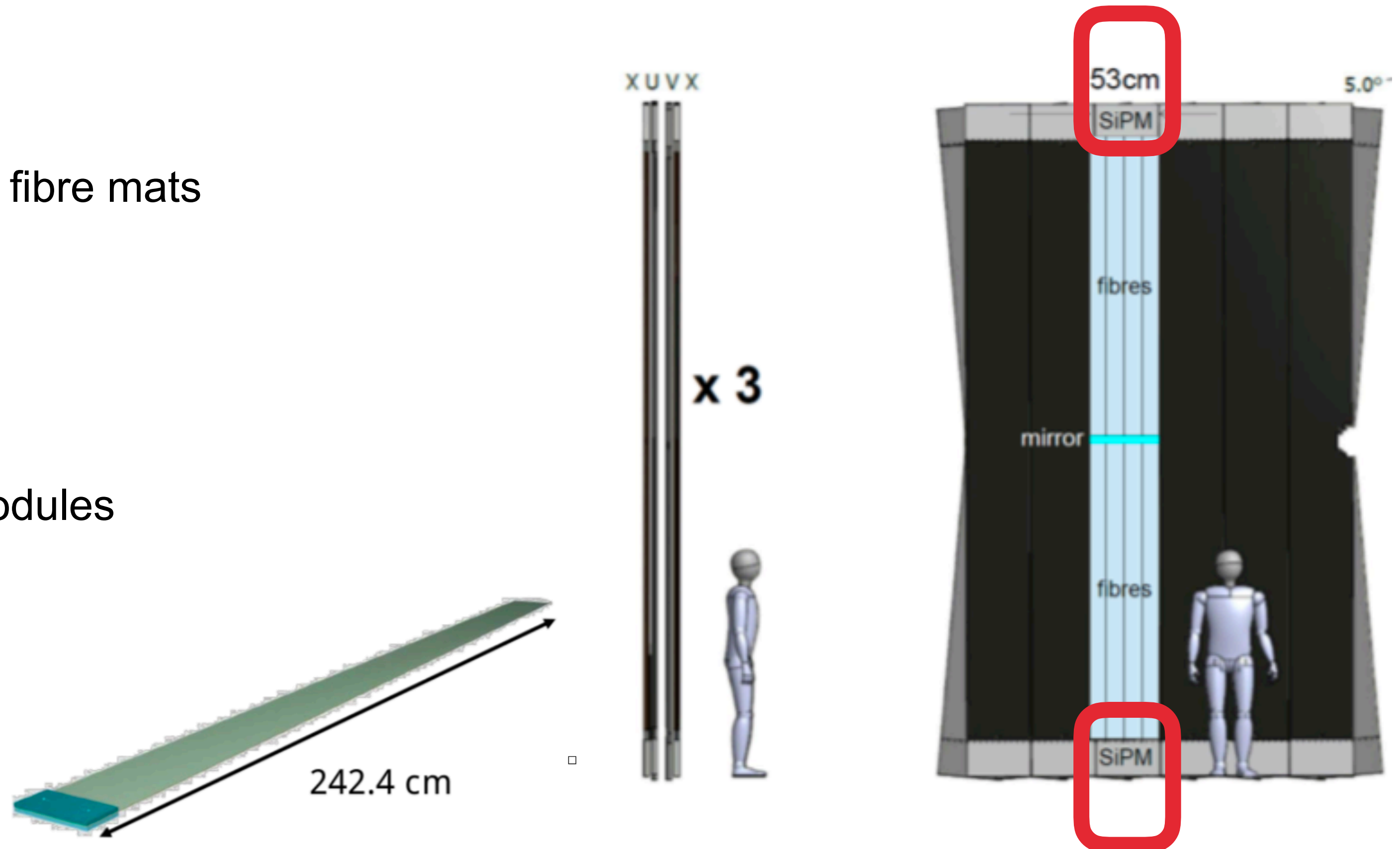
- Upgrade the detector for an integrated Luminosity of 50 fb^{-1} for Run 3 & Run 4 :
 - ▶ 40 MHz readout, software based trigger
 - ▶ Current tracker technology (silicon microrstrip and straw tubes) can not fulfil the requirements

- Scintillating fibre tracker:

- ▶ Based on scintillating fibres arranged into fibre mats
- ▶ Detection of scintillating light with SiPMs

- Detector design:

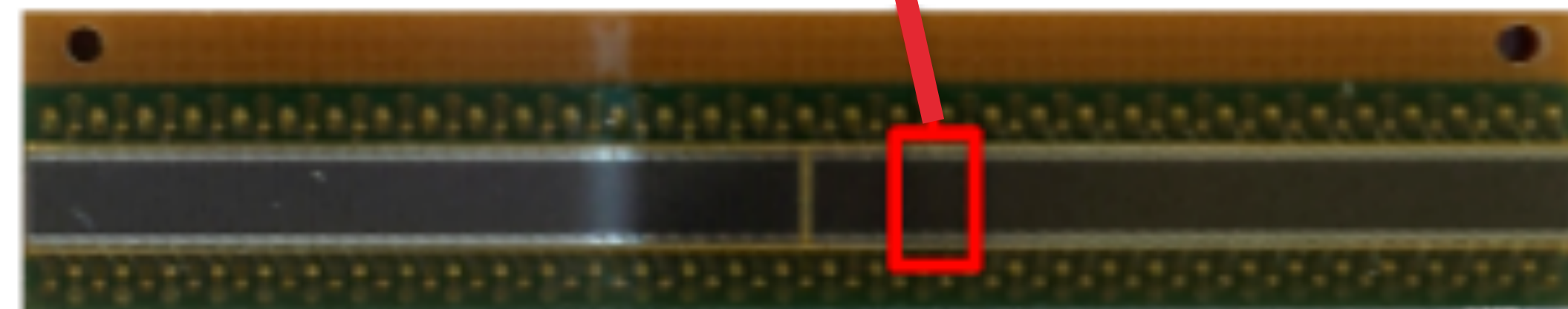
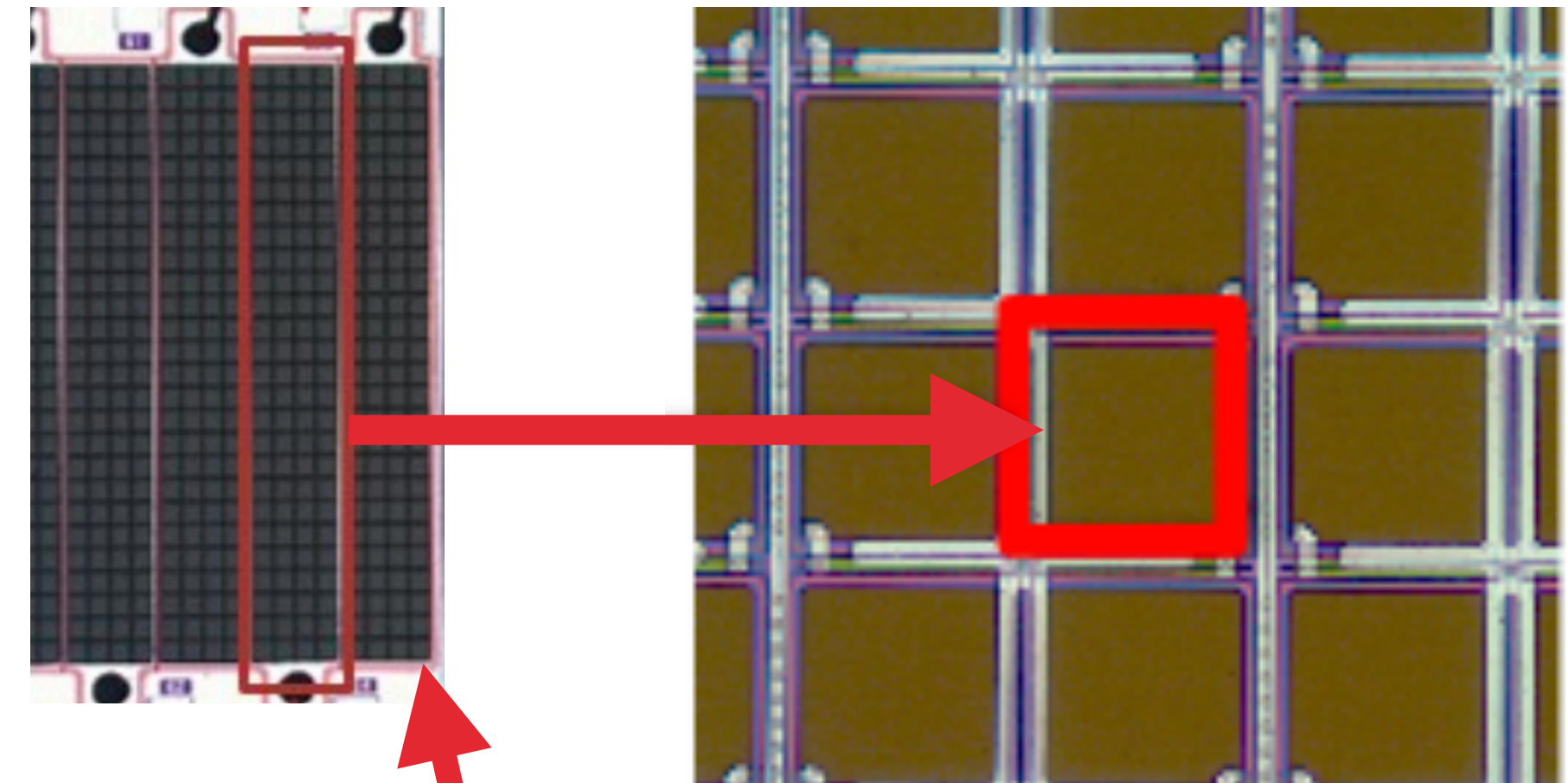
- ▶ 3 tracking stations with 4 layers of 12 modules (total 144 modules)
- ▶ Station midlayers rotated by 5°
- ▶ Each fiber mat is attached to 4 SiPMs



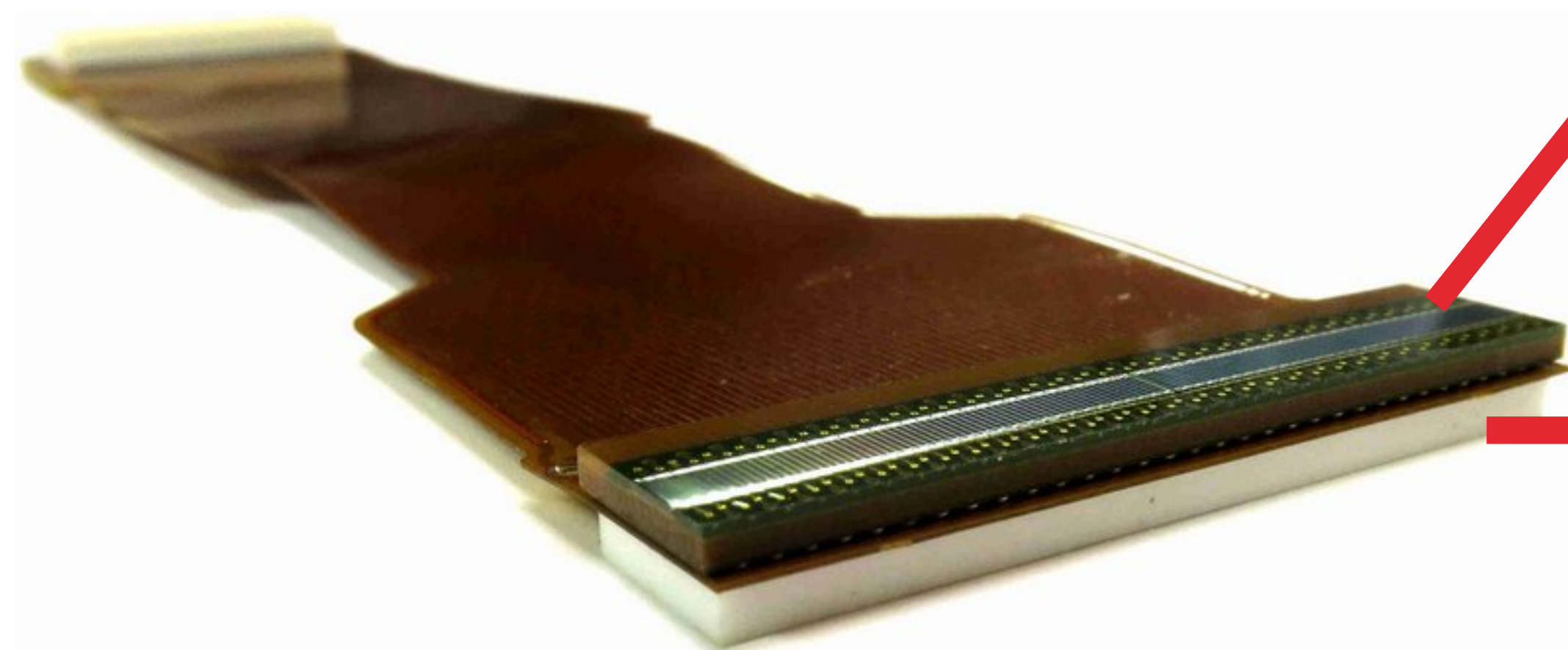
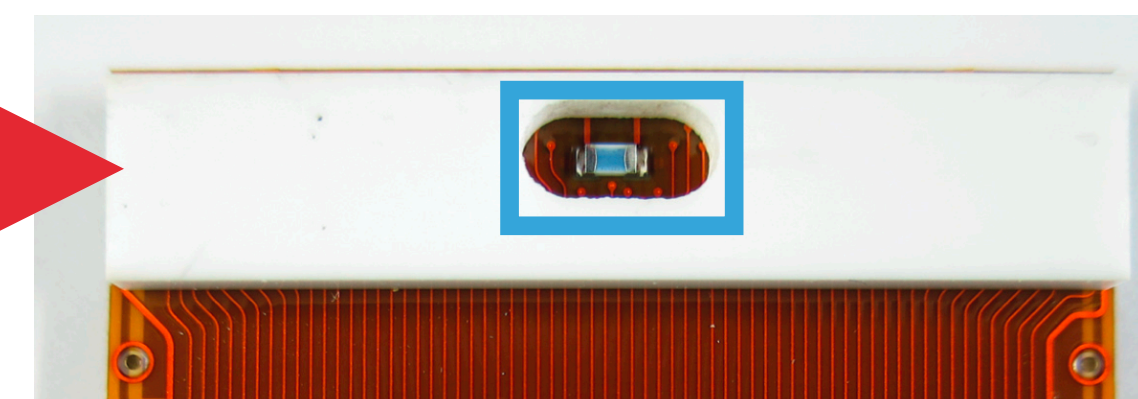
[CERN/LHCC 2014-001]

Silicon Photomultipliers

- Two silicon dies 128 channels (Hamamatsu)
- 104 pixels, electrical connected $(57.5 \times 62.5) \mu m^2$
- Silicon is protected by an epoxy layer



- Stiffener plate and temperature sensor
 - ▶ Devices will be operated at $-40^{\circ}C$



SiPM characterisation

➔ For the optimal operation point of the SiPMs, several parameters need to be studied:

- Breakdown voltage (V_{BD})
- Correlated Noise
- Dark count rate (DCR)

➔ Challenges:

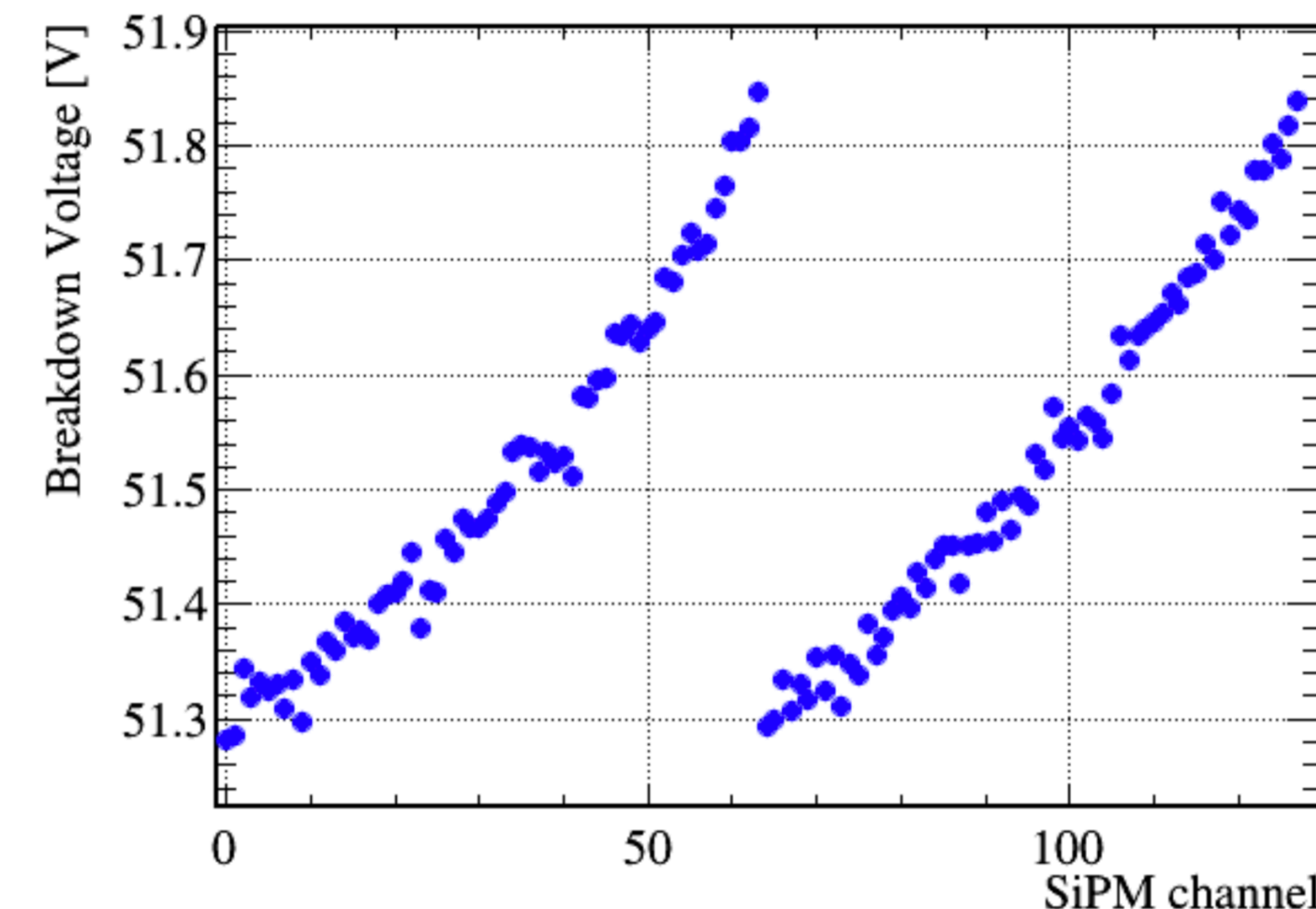
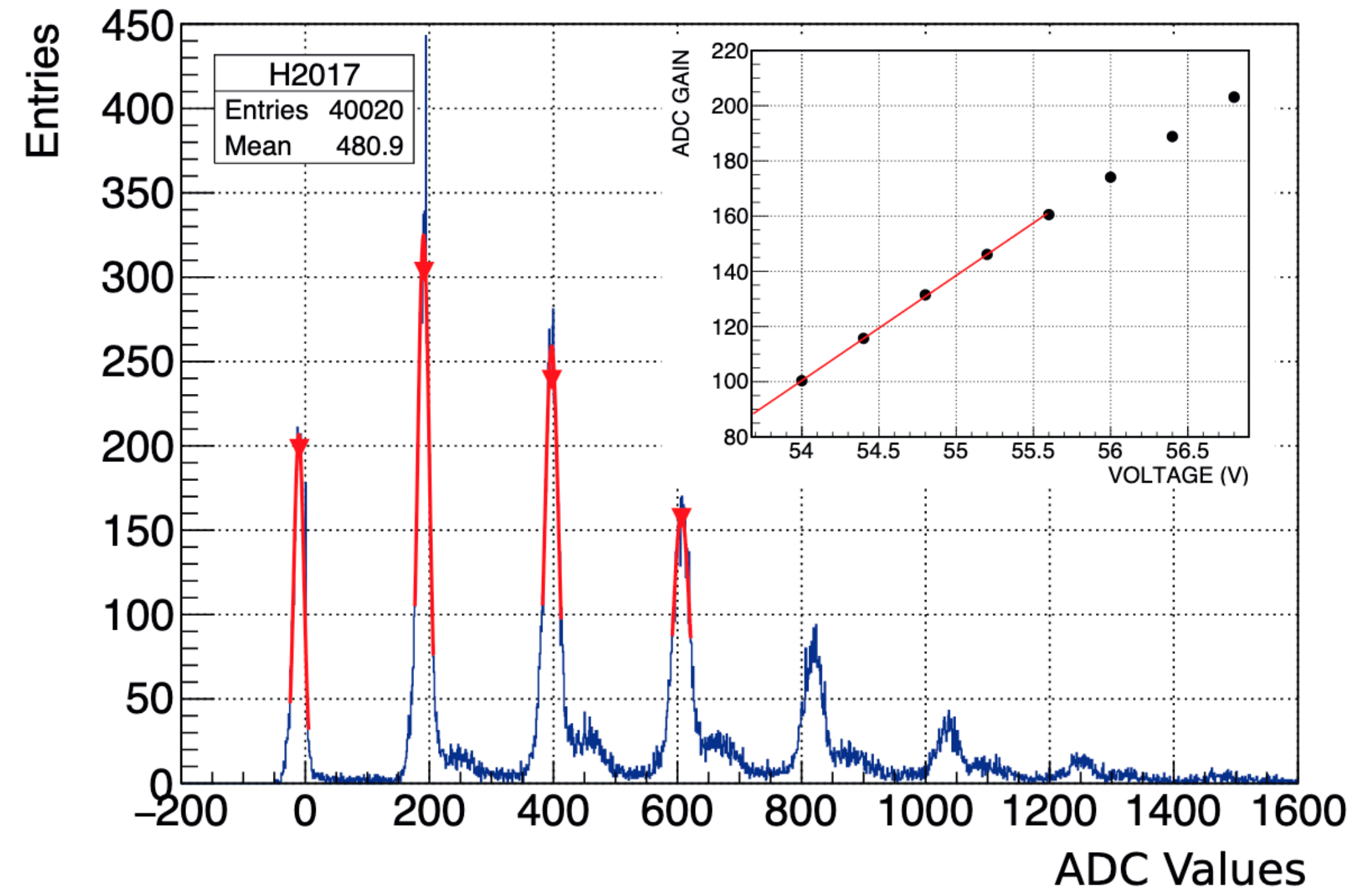
- Radiation
- Fast readout
- Temperatur dependence
- Geometry

- V_{BD} is the voltage needed to trigger the avalanche

$$Q_A \sim \Delta V = V_{Bias} - V_{BD}$$

- Measurement with multichannel charge sensitive amplifier ASIC (VATA64)

- ▶ Measure dark spectrum for pedestal determination
- ▶ Measure low photon spectrum with fast light pulses
- ▶ Determine gain from distance of the photon peaks
- ▶ Extrapolate V_{BD} from fit to 0 gain



Dark count rate (DCR):

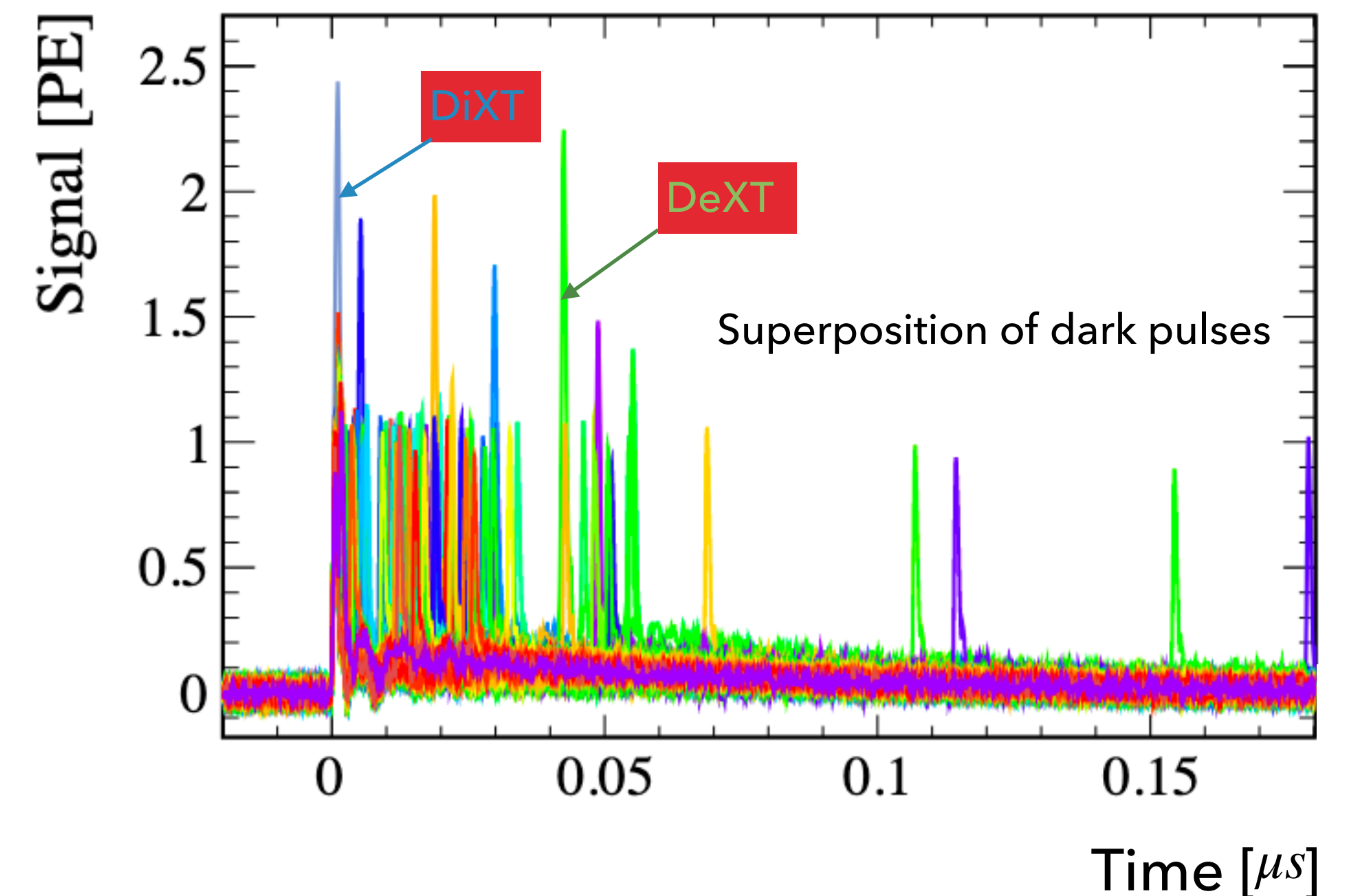
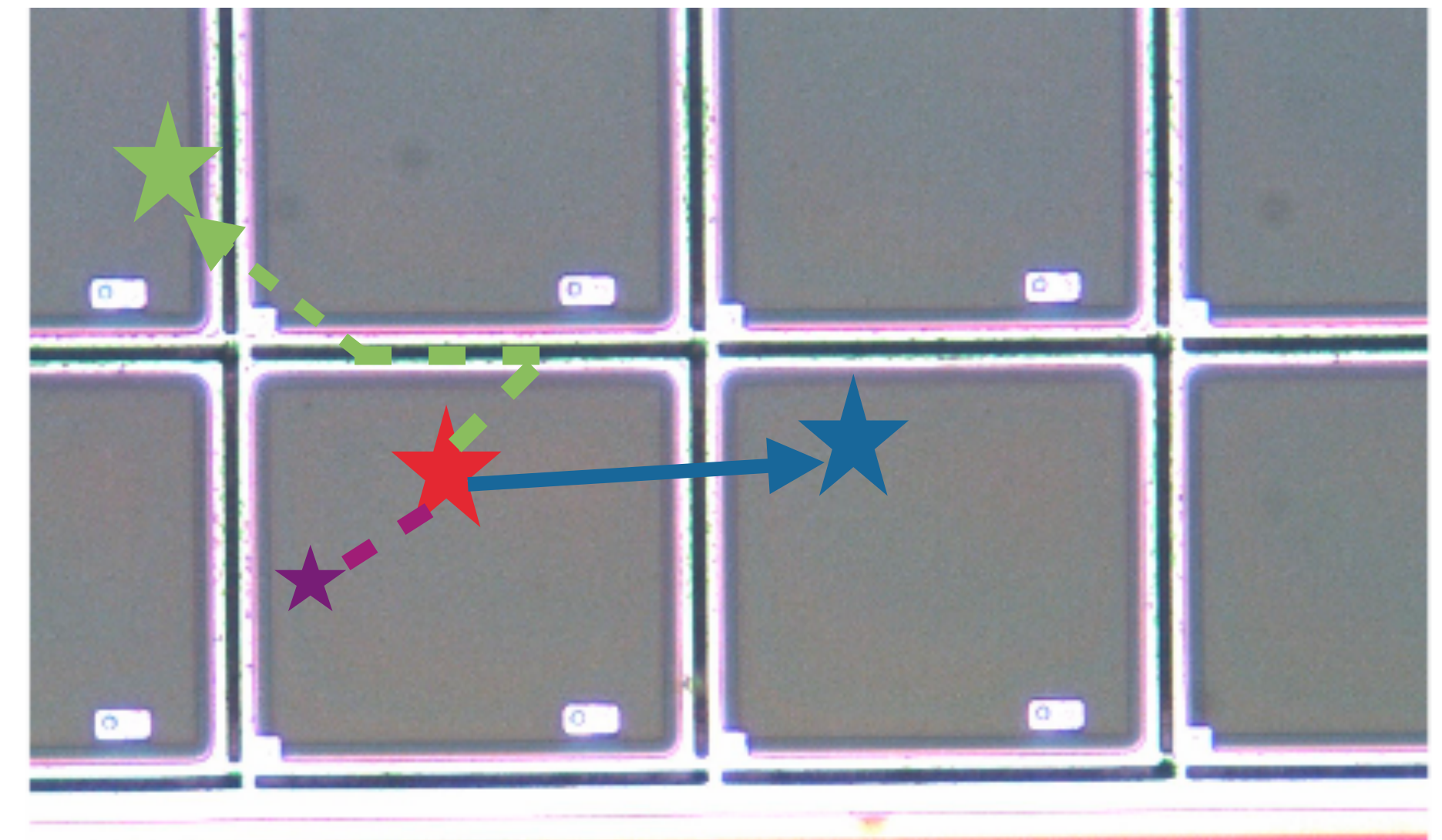
- ▶ Random thermal generated pulses
- ▶ Proportional to the active area
- ▶ Increases with temperature and radiation

Correlated Noise

- ▶ Direct pixel-to-pixel cross-talk (DiXT)
- ▶ Delayed pixel-to-pixel cross-talk (DeXT)
- ▶ After-pulse (AP)

Analysis with an oscilloscope: [\[arXiv:1808.05775\]](https://arxiv.org/abs/1808.05775)

- ▶ Acquire a large number of dark pulses
- ▶ Analyse offline

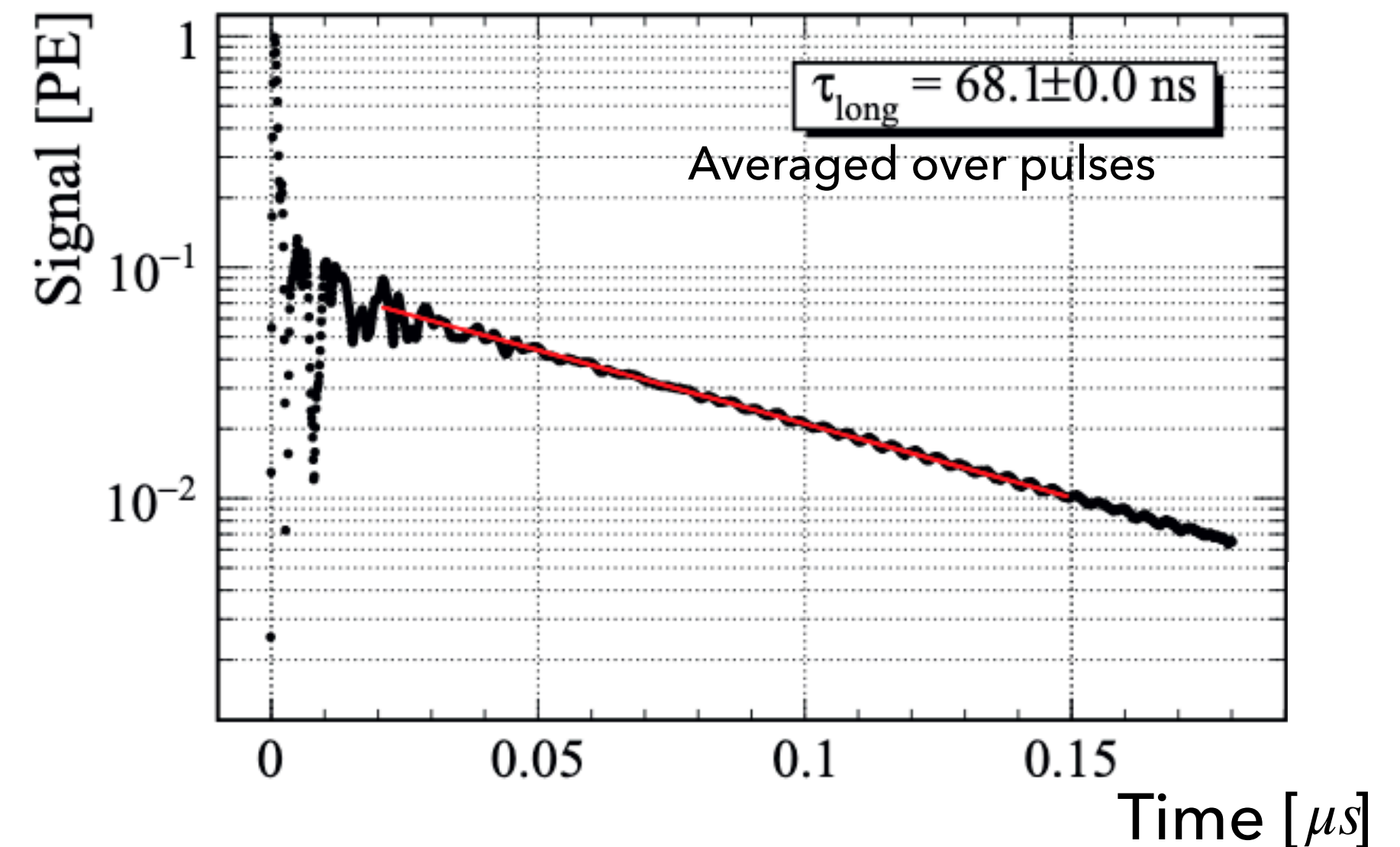
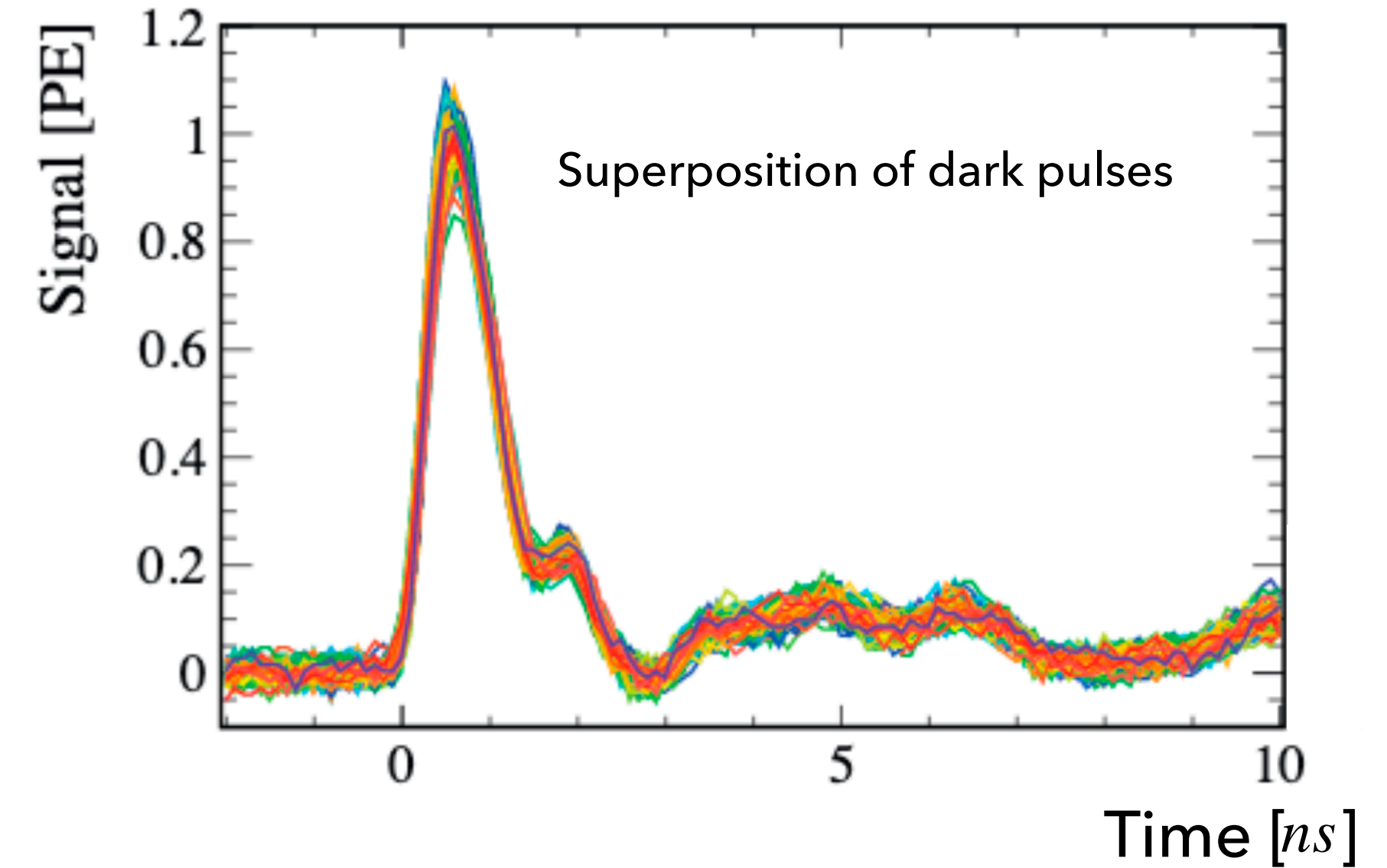


● **Pulse has fast and slow components:**

- ▶ $\tau_{short} < 1.0$ ns dominated by acquisition bandwidth
- ▶ τ_{long} characterises the device
- ➔ determined with an exponential fit

➔ Pixel recovery time:

$$\tau_{rec} = 70\text{ns (H2017)}$$



SiPM assembling

○ **Groups of 4 SiPMs are mounted in cold box and operated with a common bias voltage supply:**

- ▶ Grouping of devices with similar V_{BD}
 - ➔ **Compensate differences of 500mV**
- ▶ Similar total thickness



[LHCb collaboration, LHCb-INT-2016-019]

Devices are fully tested and characterised

1. Full electrical tests:

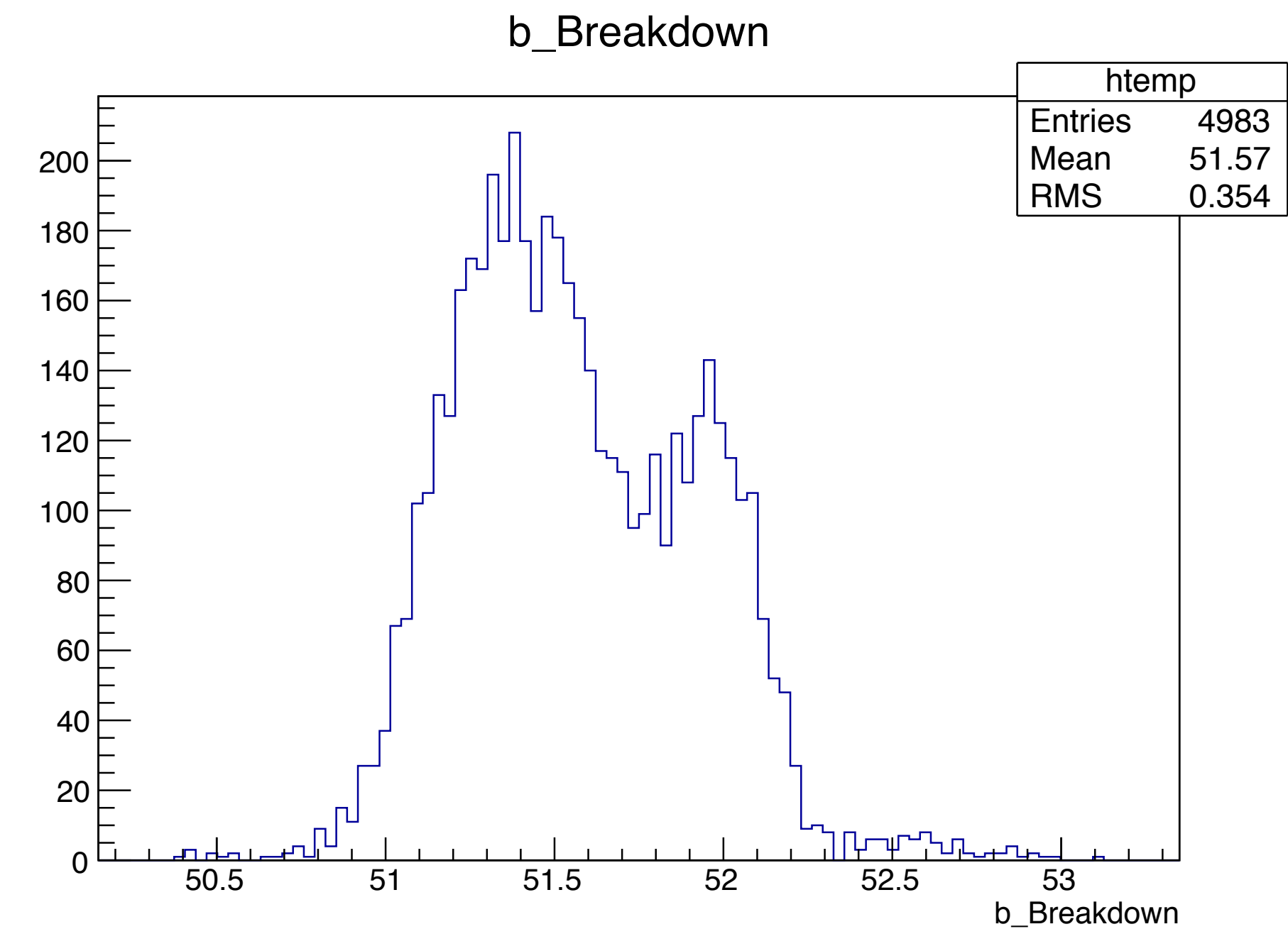
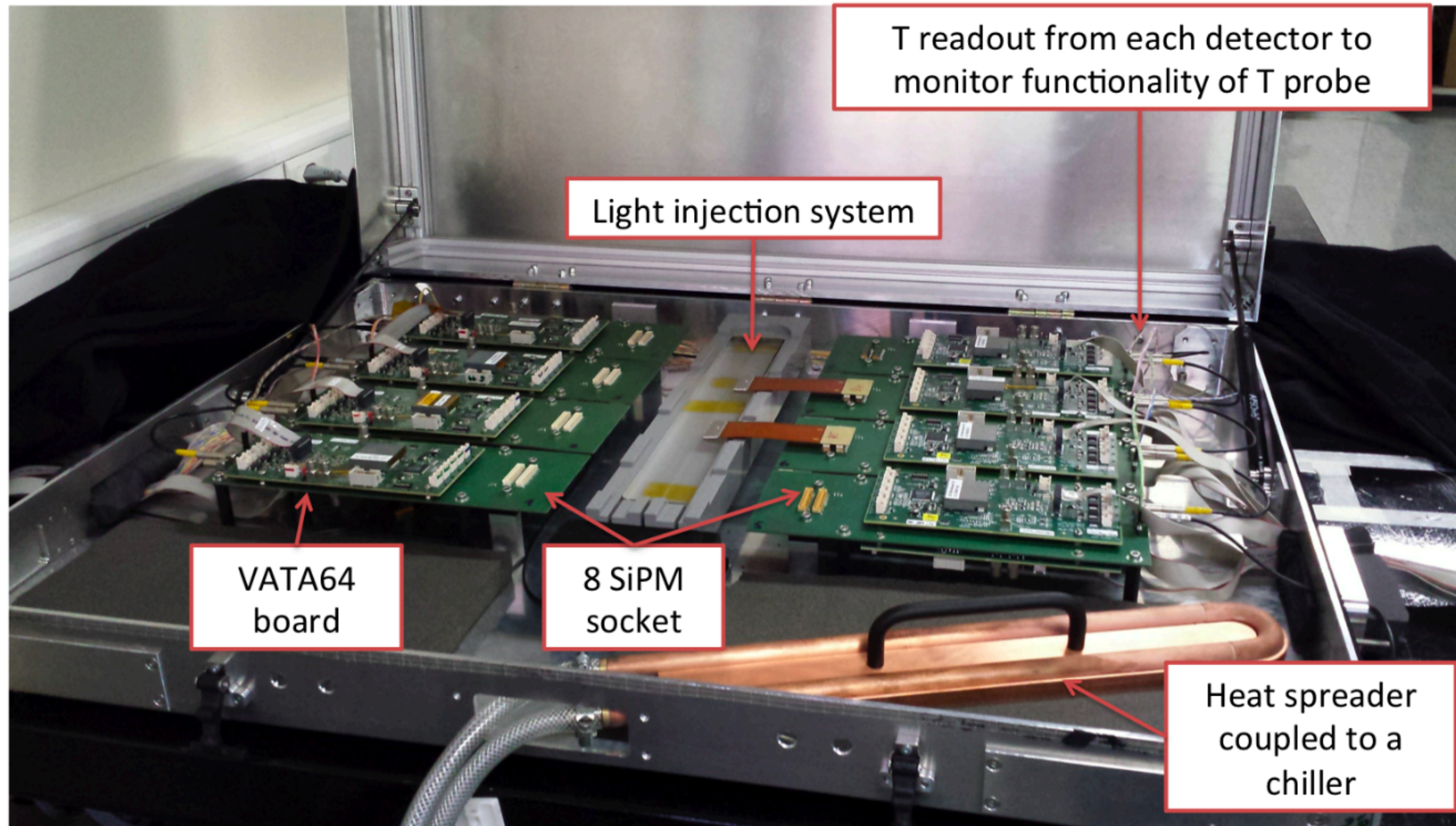
- ▶ Dead channel test
- ▶ Temperature sensor test
- ▶ V_{BD} measurement

2. Thickness measurement

3. Optical inspection



Measurement with multichannel charge sensitive amplifier ASIC (VATA64)



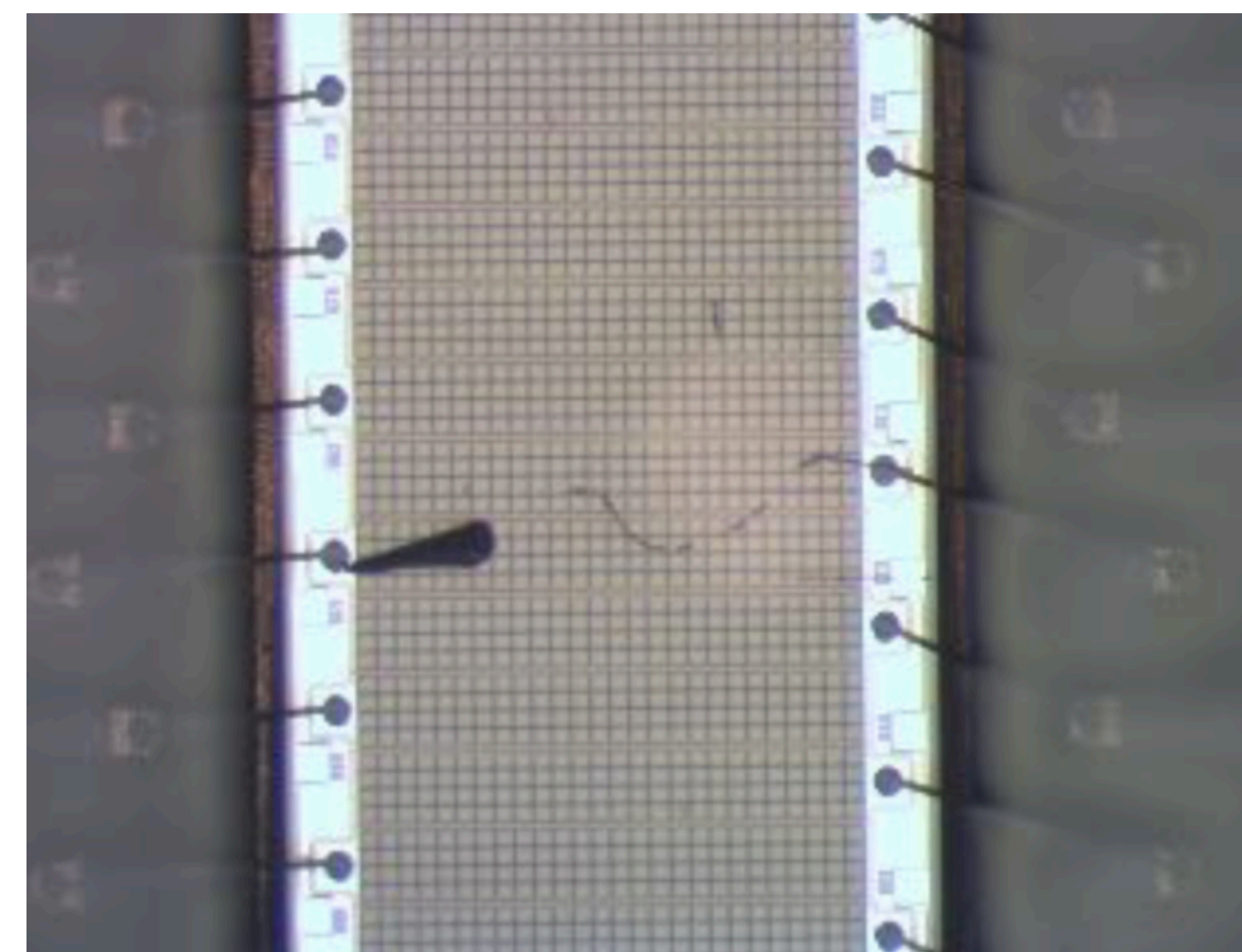
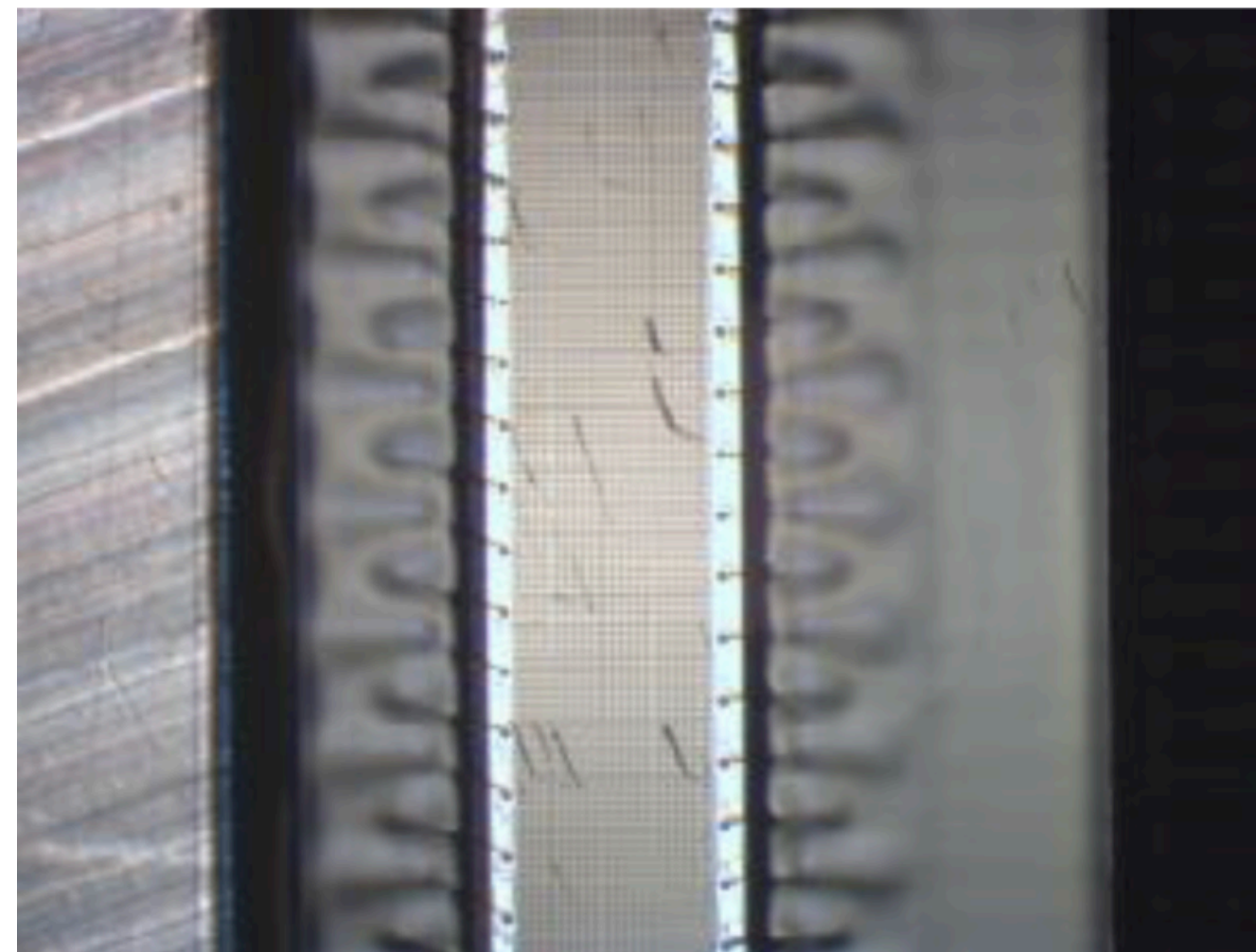
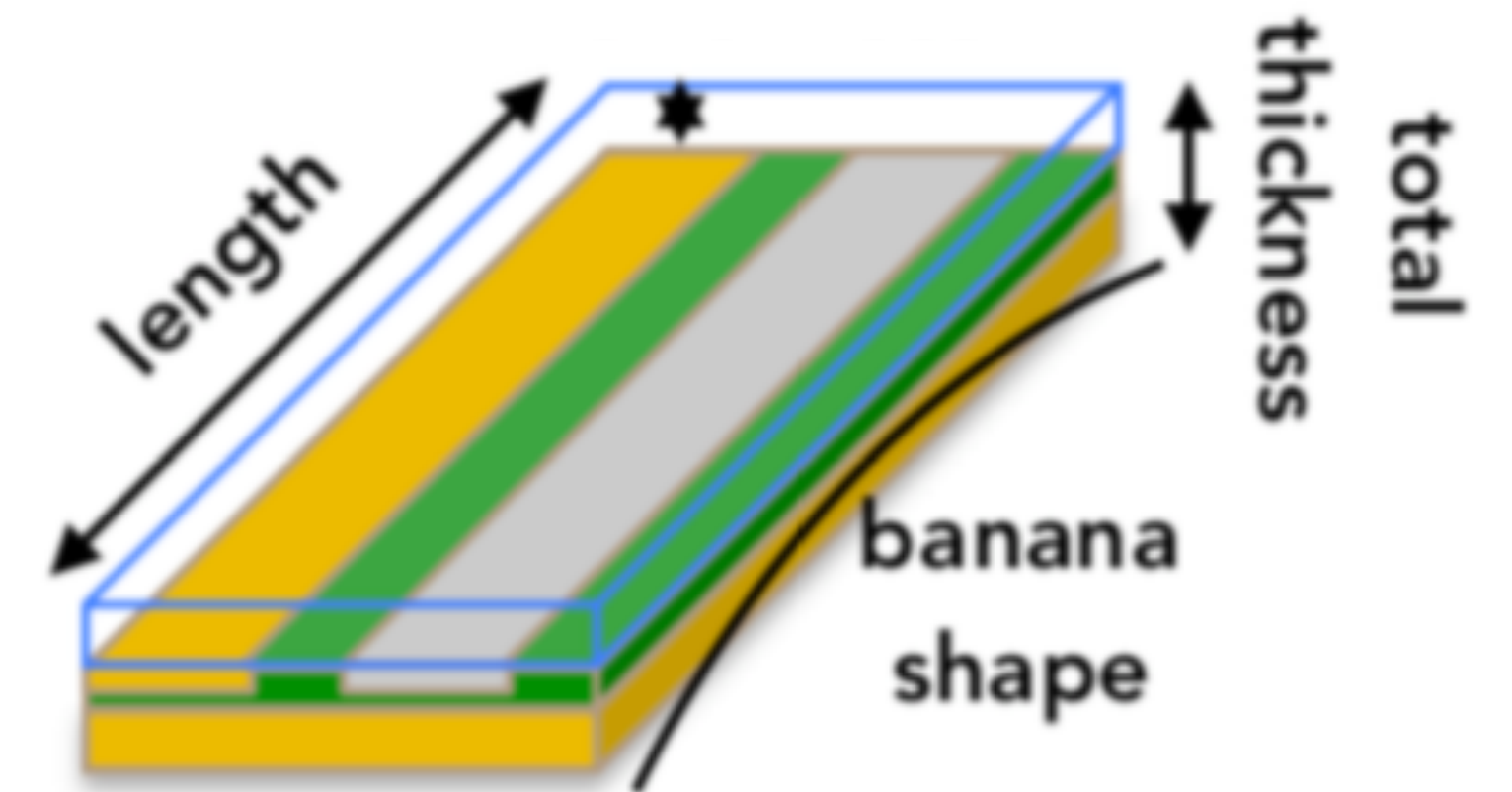
● Thickness measurement with optical focusing system under a microscope

● Mean deviation in thickness is evaluated:

▶ In general a banana-like shape is observed

● Devices with a deviation $>100 \mu\text{m}$ are considered as bad

● Optical inspection via microscope



- ◎ **Assembling summary:**

- ▶ Measured all 5000 SiPMs
- ▶ 1.5% discarded due to optical imperfections
- ▶ 0.6% discarded due to electrical issues

- ◎ **SiPMs fulfil all expectations**

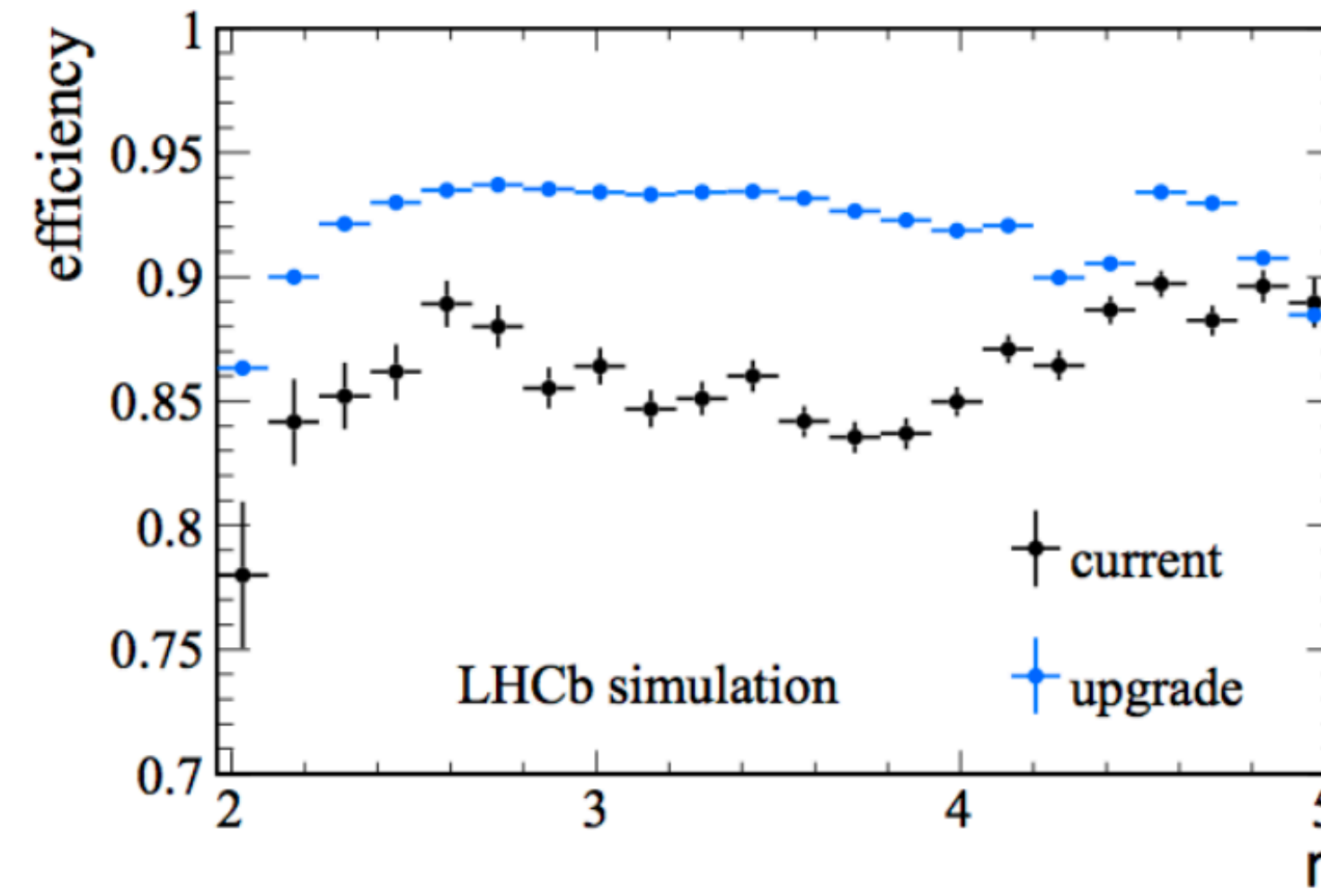
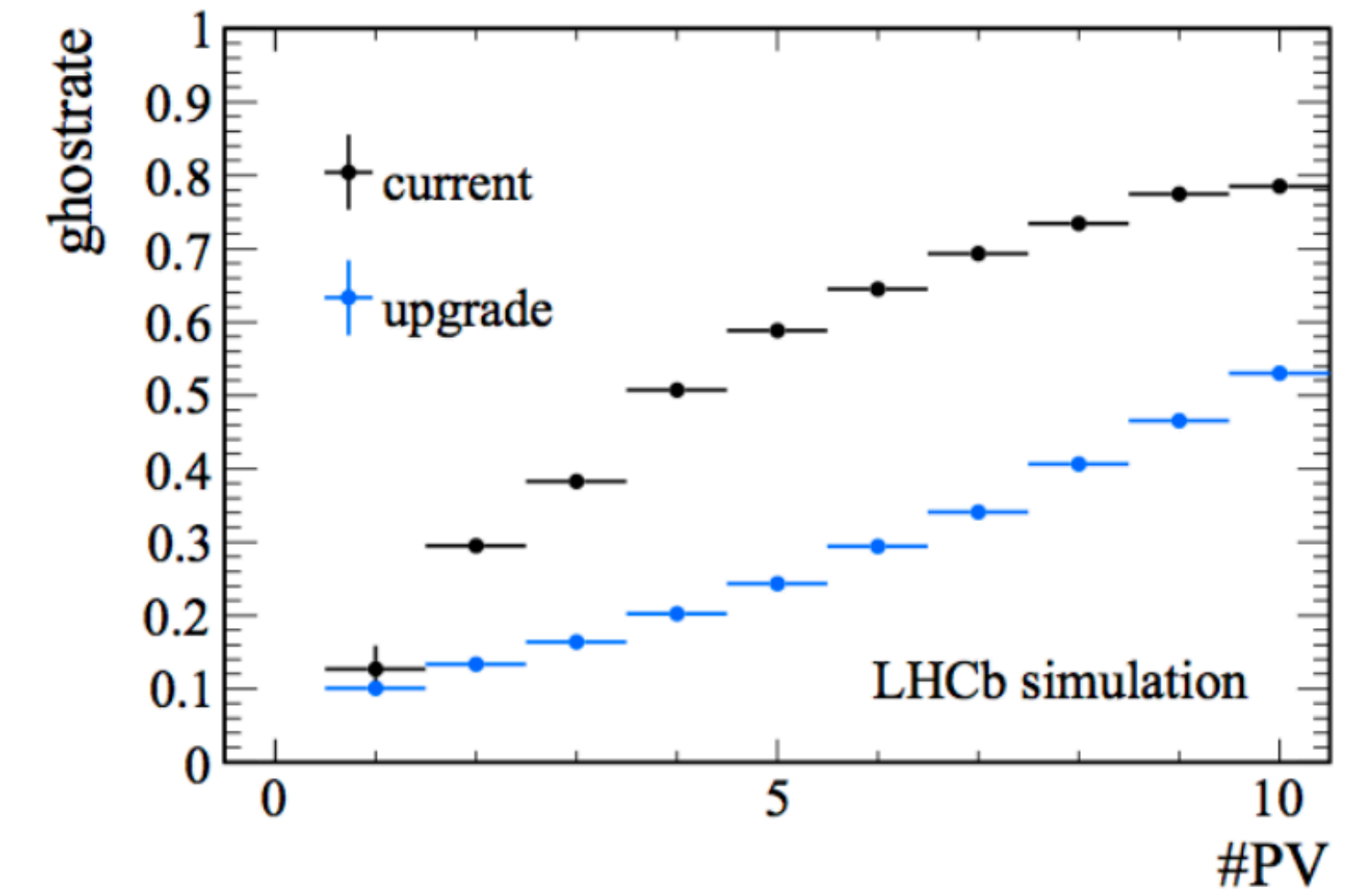
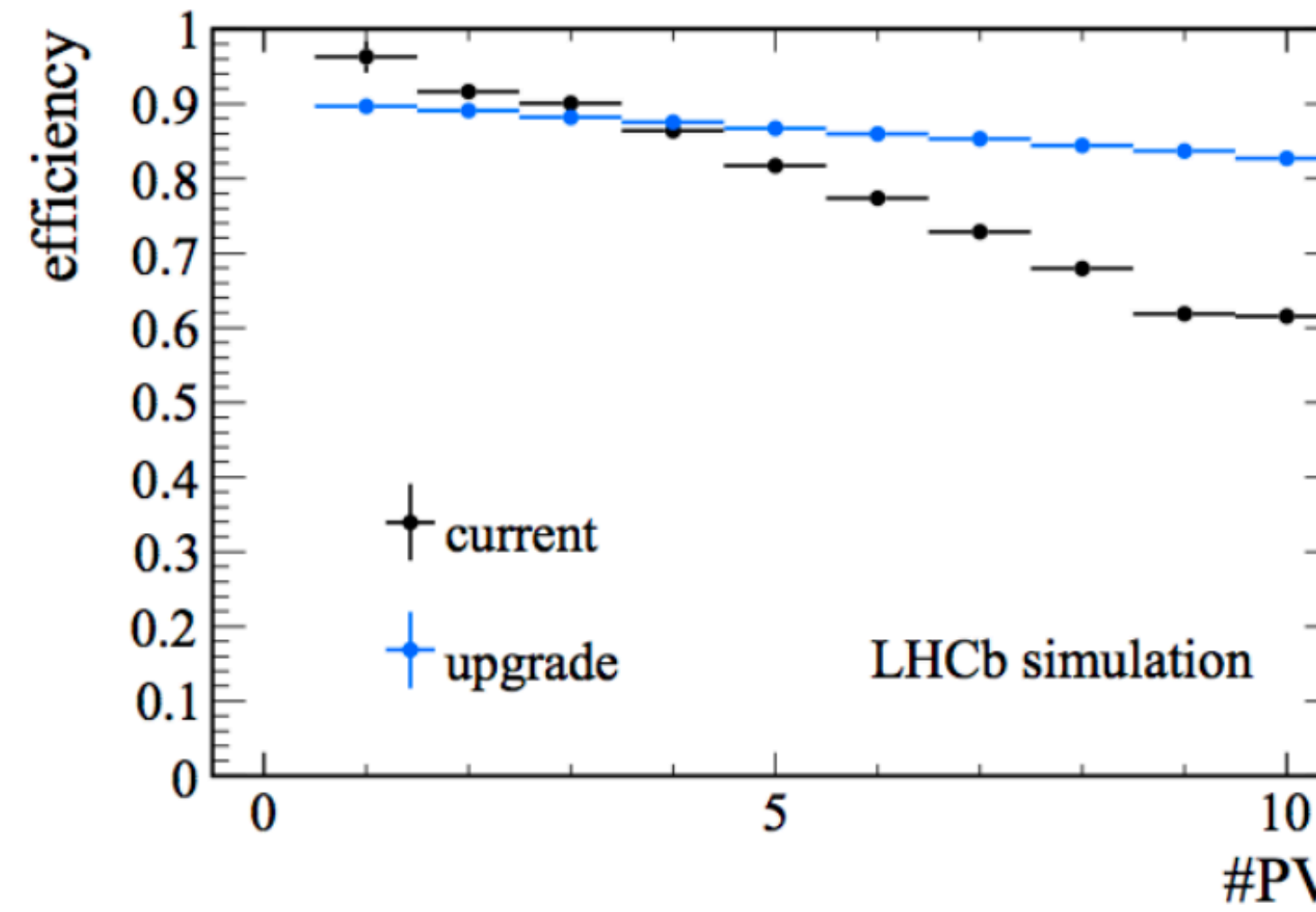
- ◎ **Currently the SciFi modules are assembled**

- ▶ **Preparation for the installation next year**

Backup

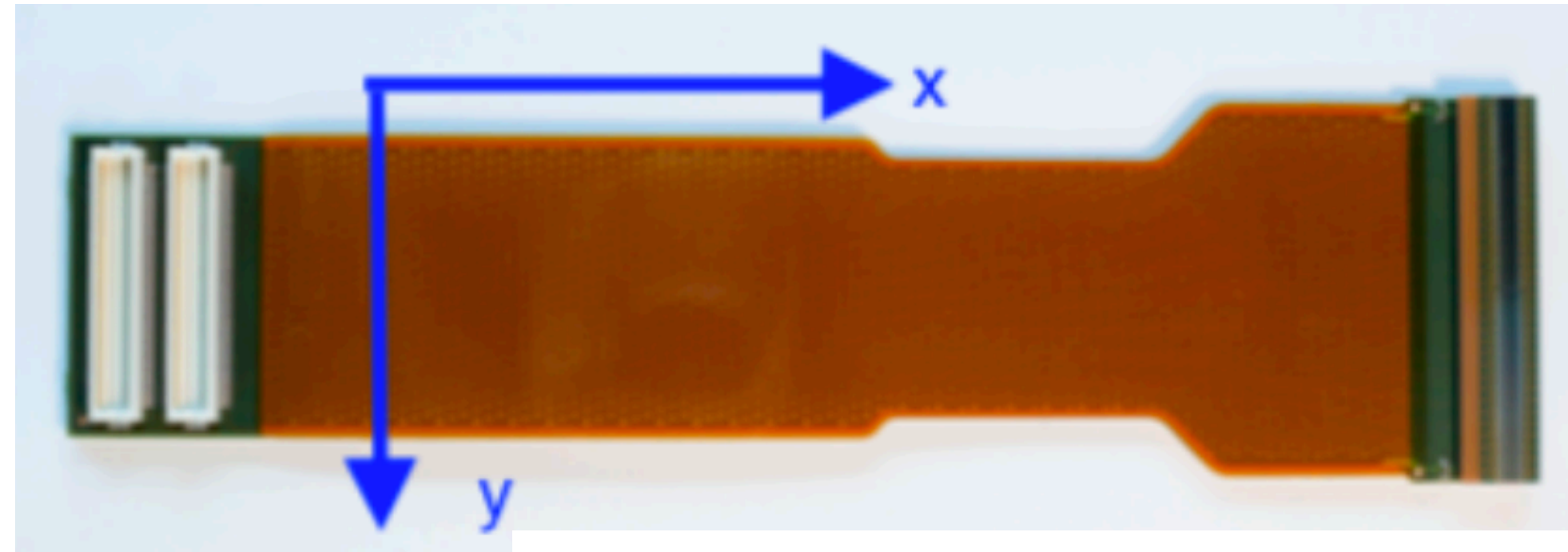
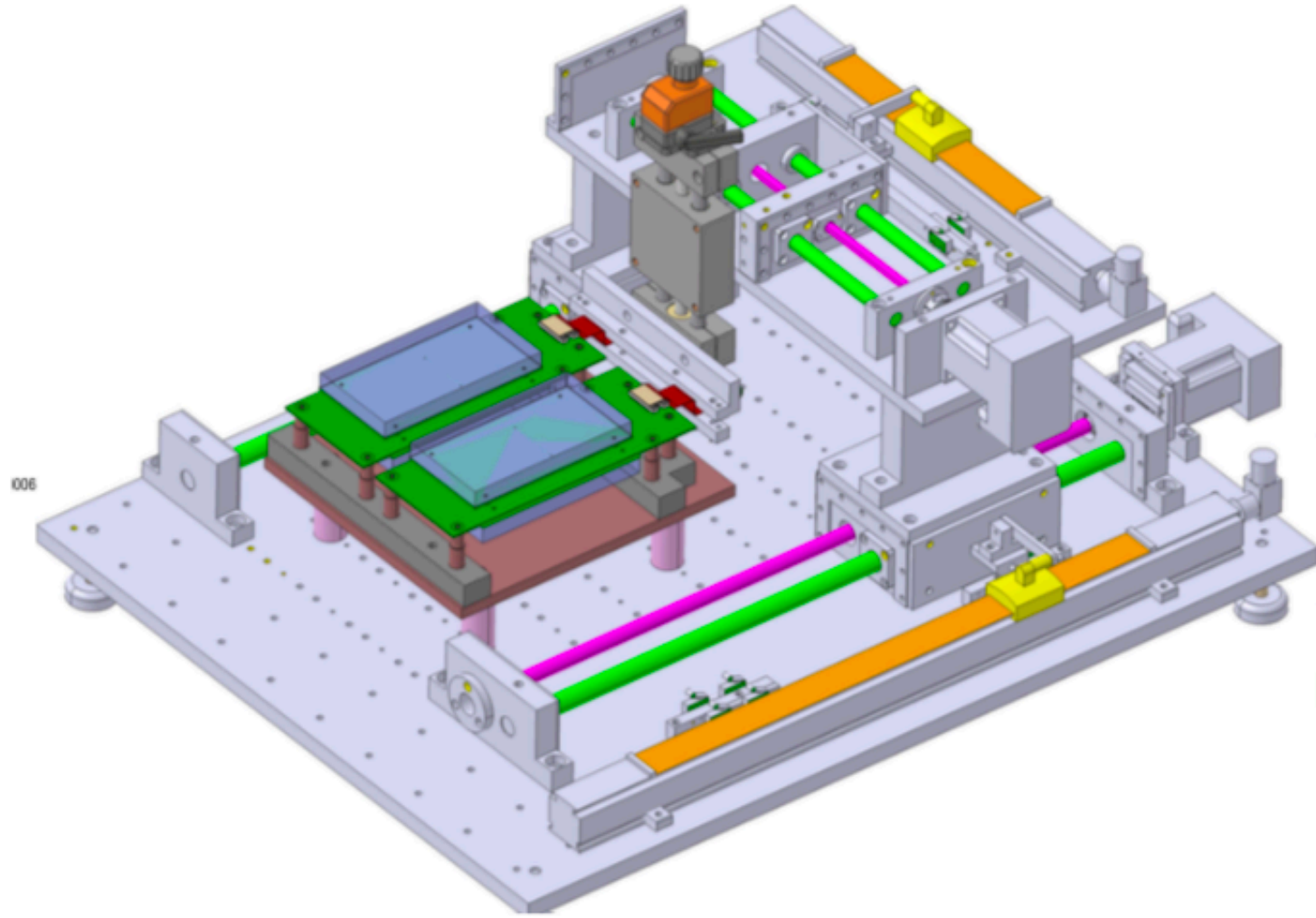
Requirements :

- Hit detection efficiency higher than 98%
- Spatial resolution better than 100 μ m
- 40MHz readout without dead time
- Operation in radiation environment, fibres 3! (neutron shielding) + 100 Gy ionising dose
- Low material with $X/X_0 \leq 1\%$ per detection lay



Tests of the mechanical stability:

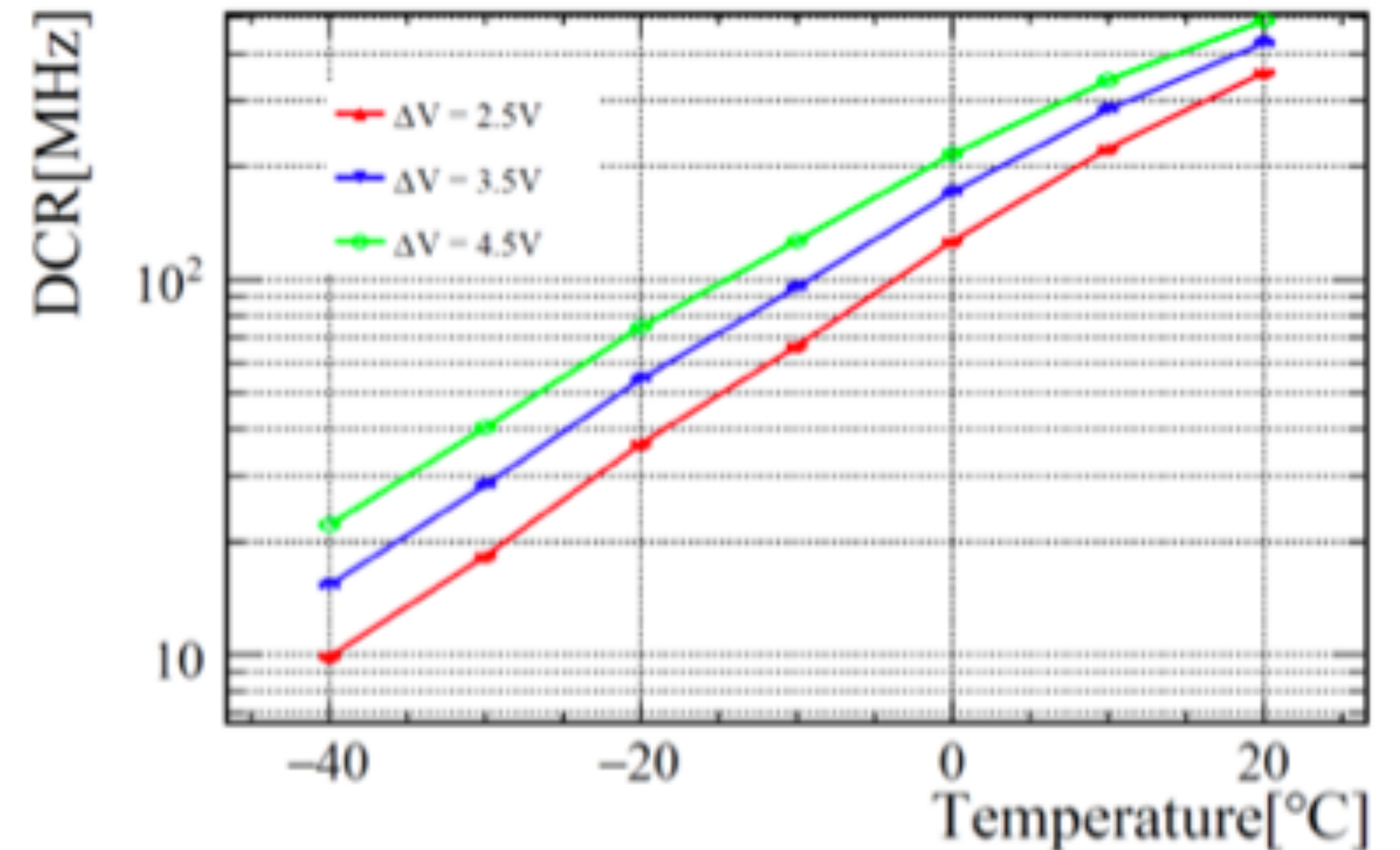
➔ After 1000 cycles of displacement in y directions channels start to break



Simulation of aging with thermal cycling

Irradiation tests:

➔ Increase of DCR from 10kHz at room temperature to 15MHz after annealing at -40°C



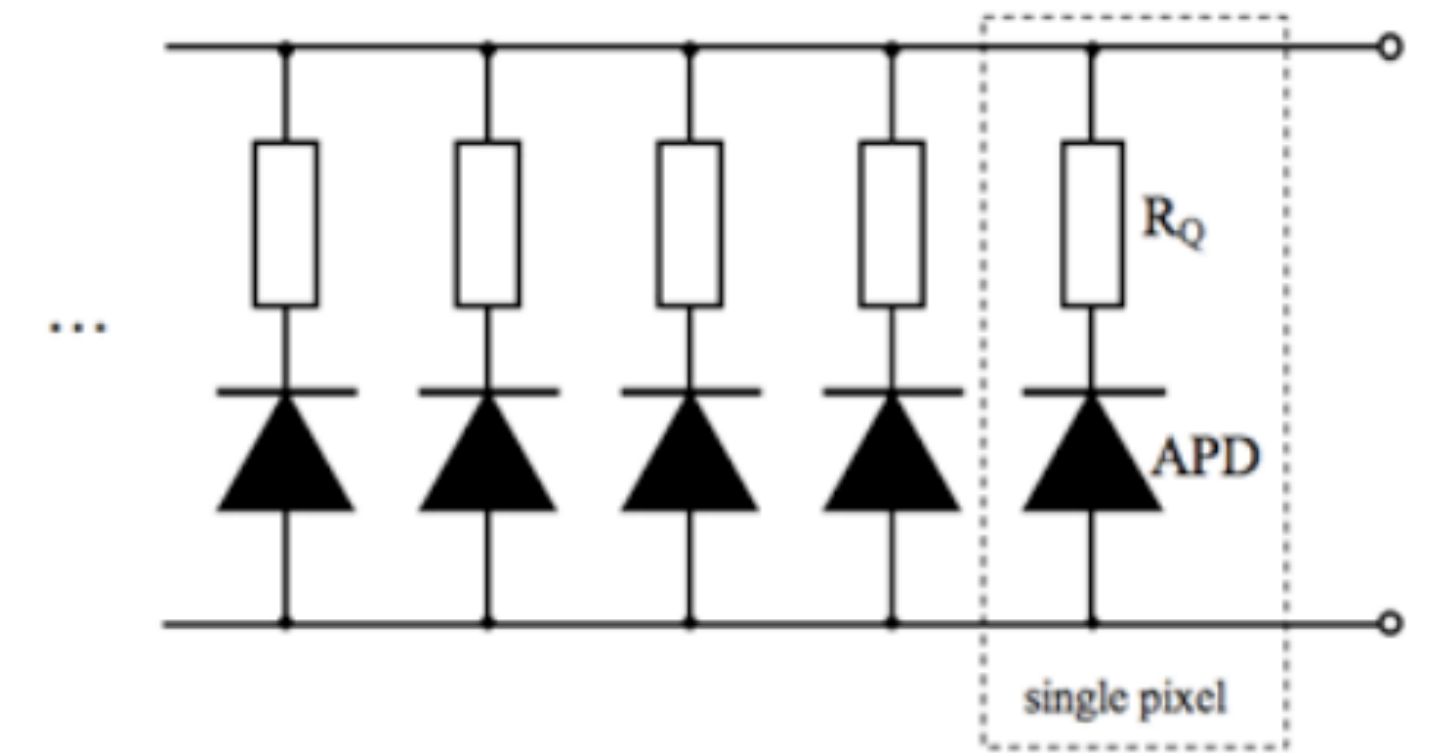
SiPMs are connected pixels of Avalanche Photodiodes (APDs)

Working principle:

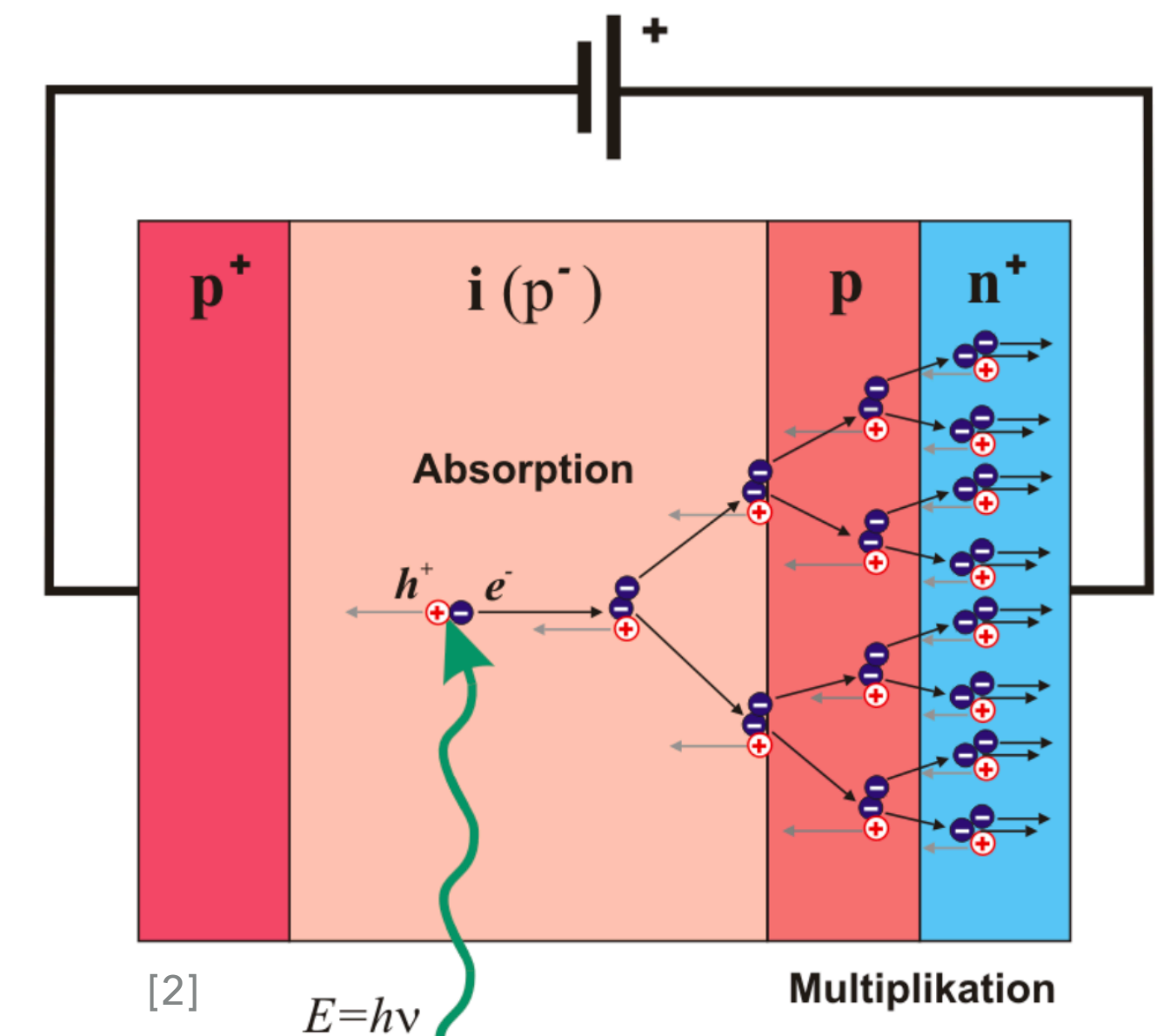
- Operated in Geiger-Müller mode with reverse bias voltage V_{Bias}
- An avalanche effect can be observed in the high electric field region
- The voltage necessary to obtain a gain larger than 1 is called break-down voltage V_{BD}
- The gain is proportional to the over-voltage:

$$Q_A \sim \Delta V = V_{Bias} - V_{BD}$$

- The avalanche is quenched by R_Q



[1]

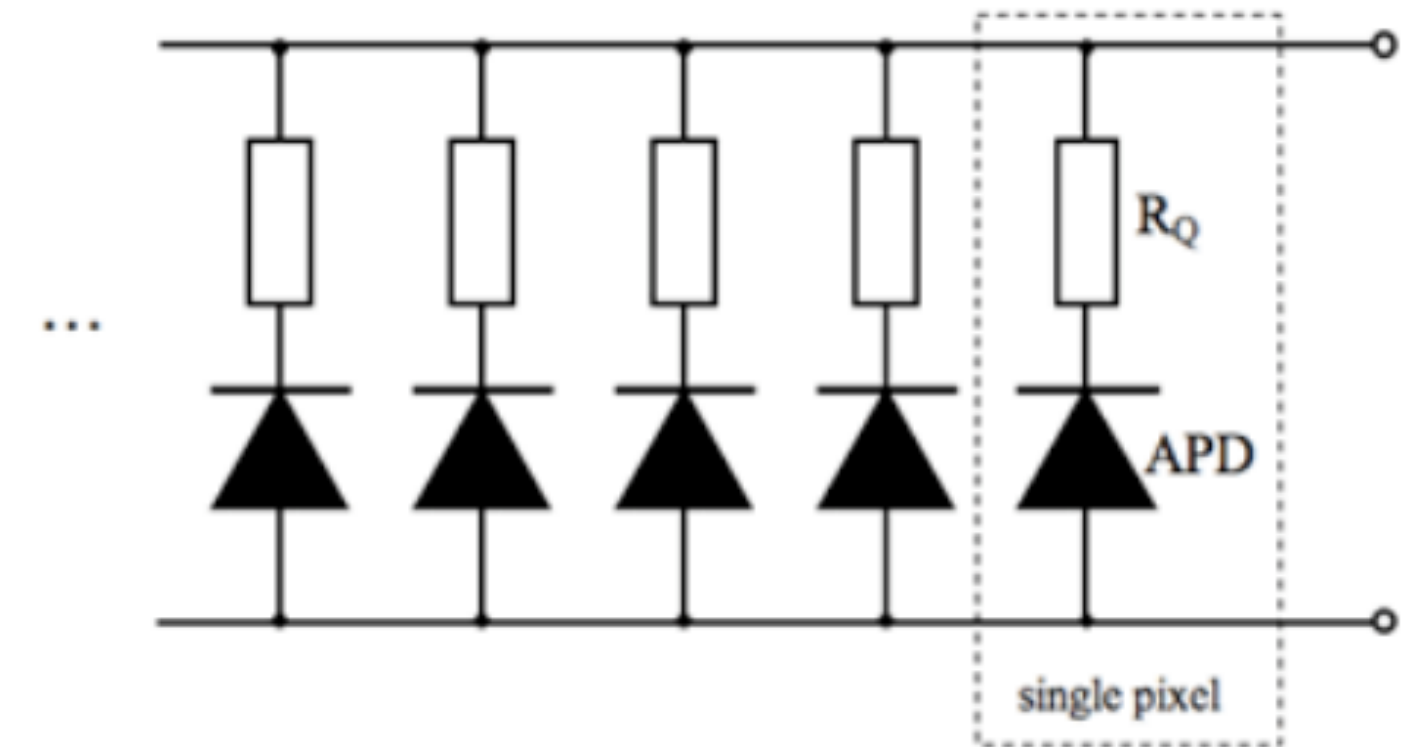


[2]

[1] [<https://hub.hamamatsu.com/us/en/technical-note/electrical-optical-sipm-properties/index.html>]

[2] [<https://de.wikipedia.org/wiki/Avalanche-Photodiode>]

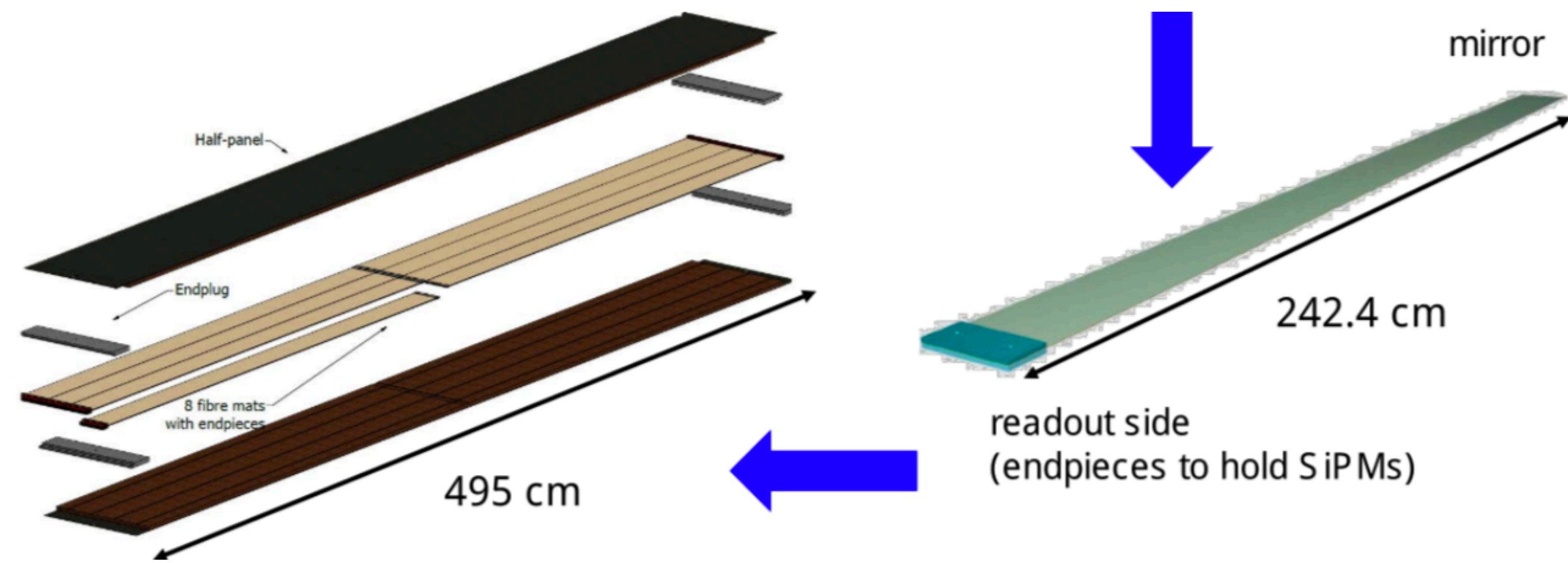
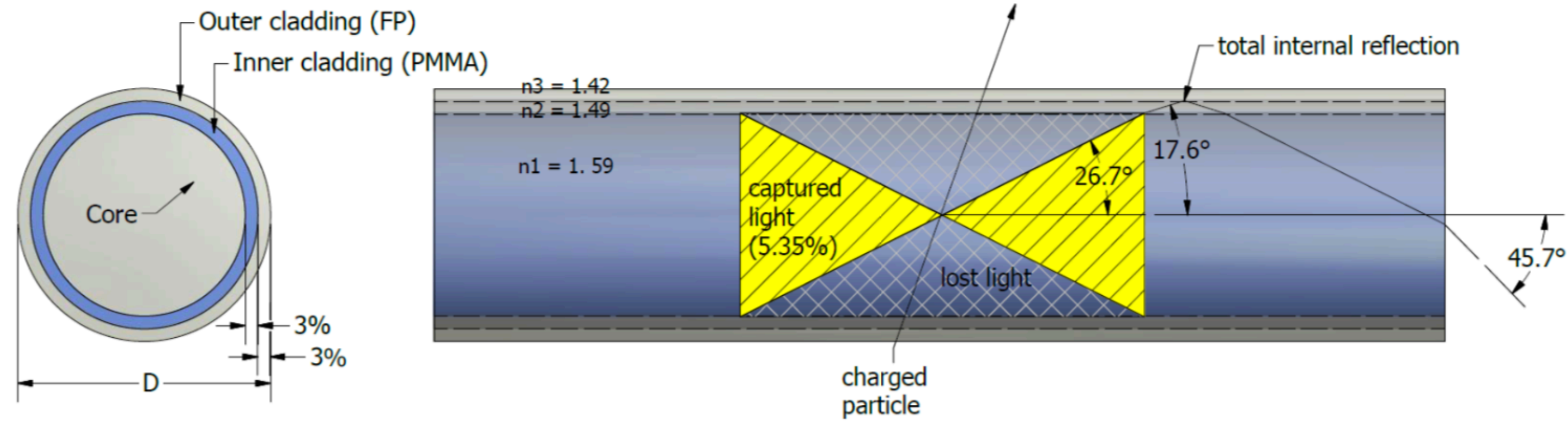
● SiPMs are connected pixels of Avalanche Photodiodes (APDs)



● SiPMs are affected by different noise sources:

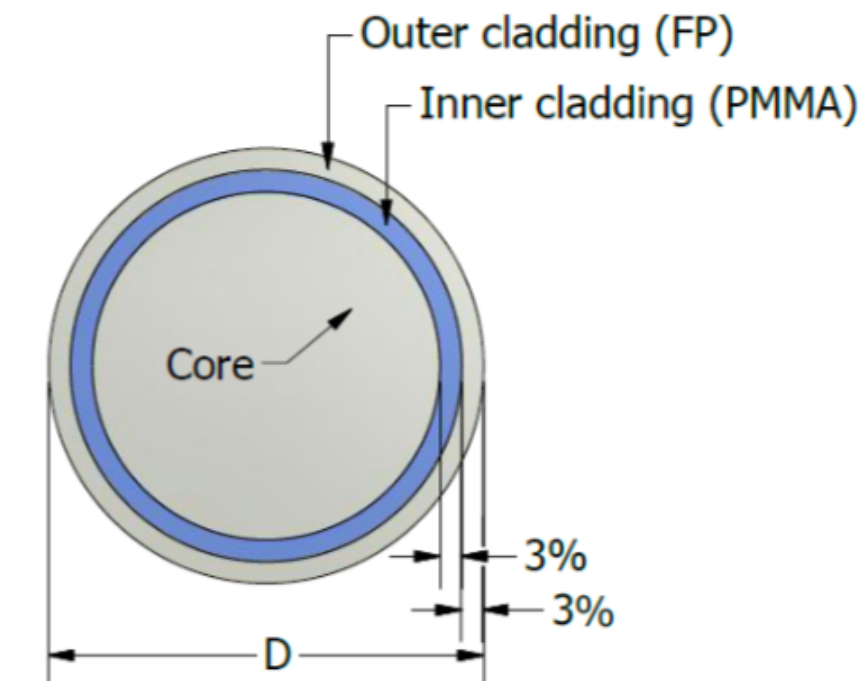
- ▶ Studie characteristics for optimised operation of the device
- ➔ analyse the waveform





● Scintillating fiber mats:

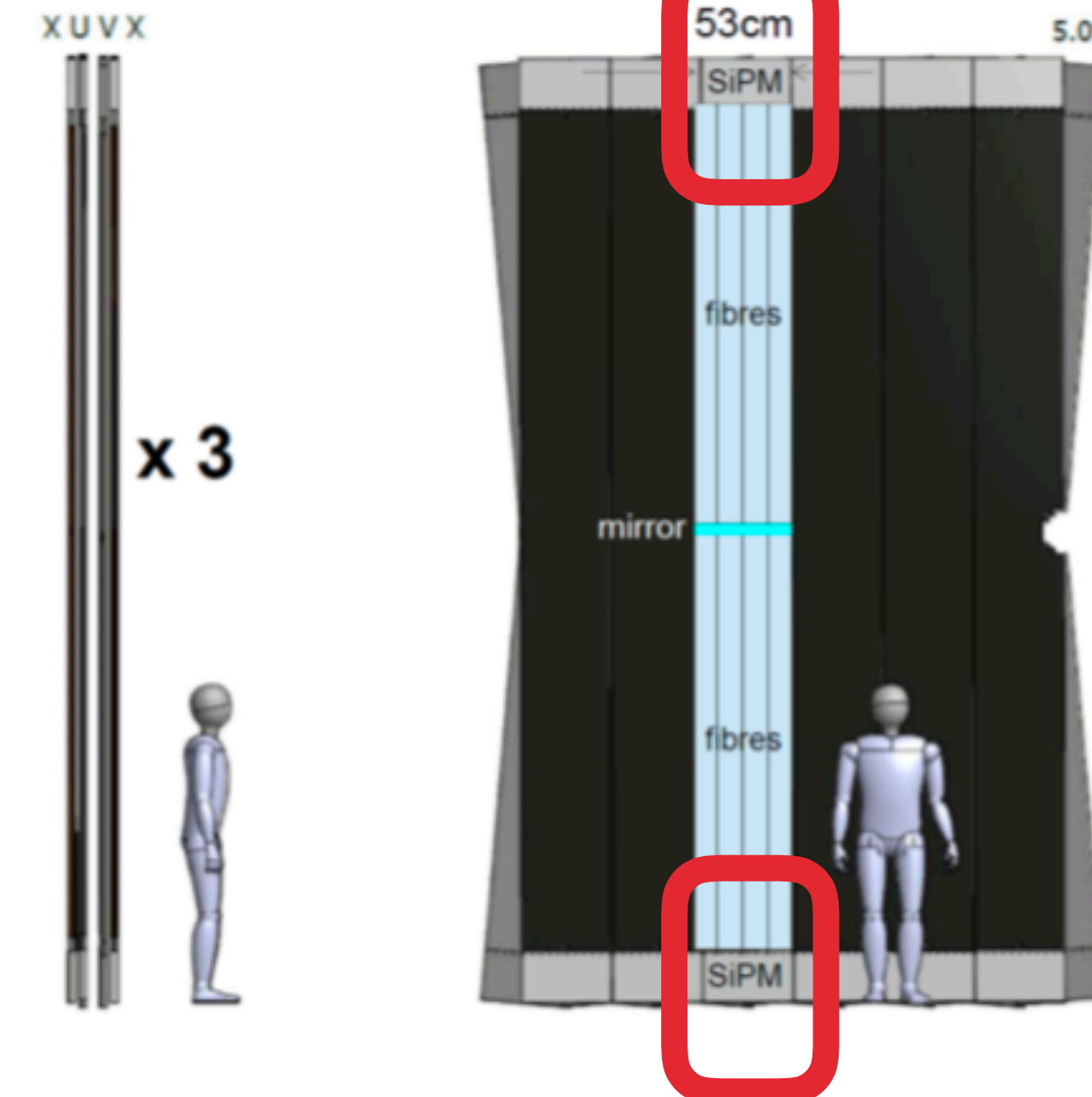
- ▶ Energy deposition by charged particles
- ▶ Emission of scintillating light
- ▶ El. signal is generated via Silicon Photomultipliers (SiPMs)



● Detector design:

● Fiber mat and modules

- ▶ 3 tracking stations with 4 layers of 12 modules (total 144 modules)
- ▶ Station midlayers rotated by $\pm 5^\circ$
- ▶ Each fiber mat is attached to 4 SiPMs



● **Measure photo-current in SiPM:**

▶ Approximation with

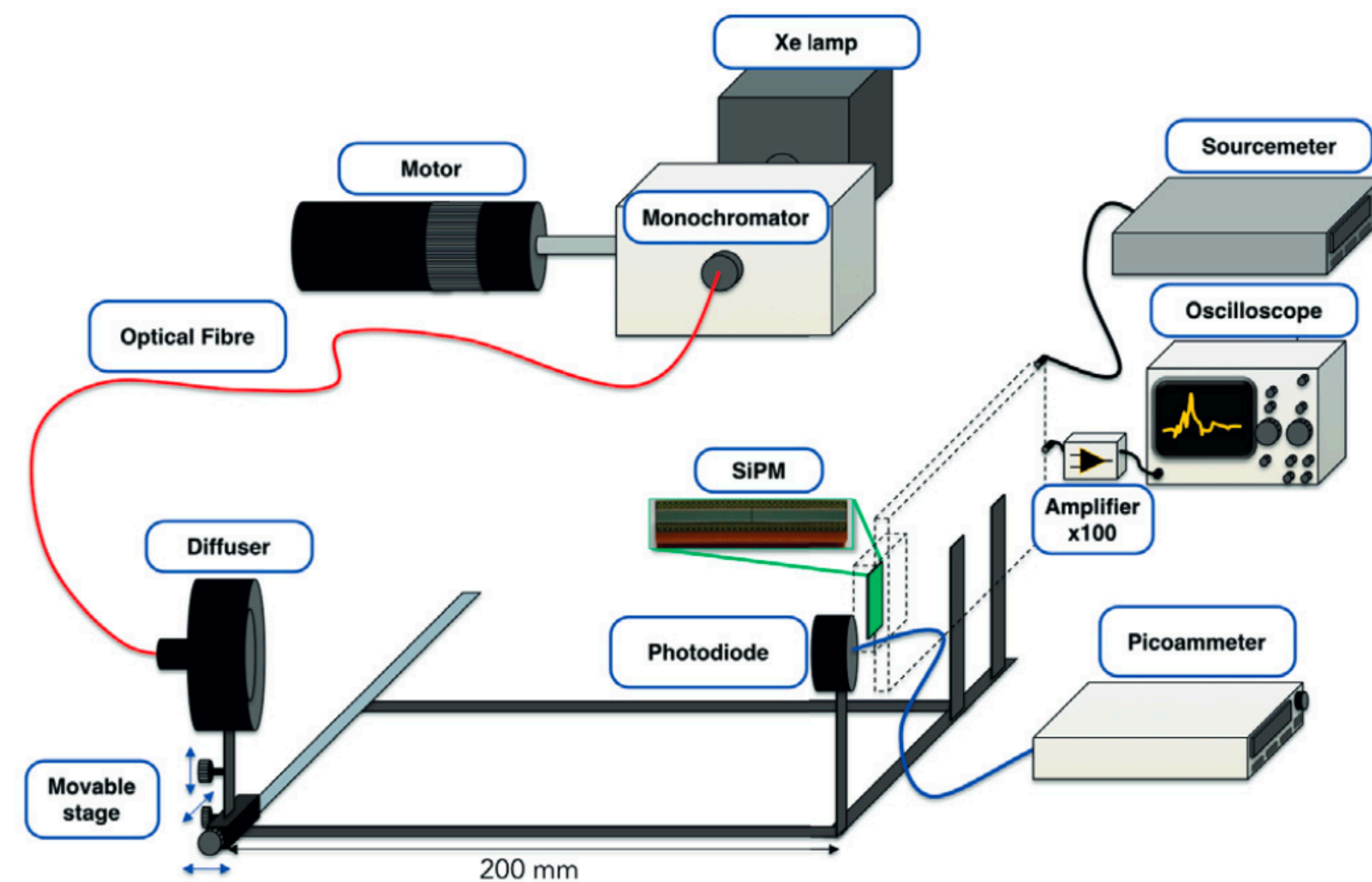
➡ Light current + dark current

➡ Corrections for correlated noise

$$I = R_{\text{detection}} \cdot G \cdot e$$

$$\text{PDE} = \text{QE}_{\text{APD}} \cdot \frac{I_{\text{light}}}{G \cdot I_{\text{PD}}} \cdot \frac{A_{\text{PD}}}{A_{\text{SiPM}}}$$

▶ Compare measured values with values from photodiode



- Measuring gain with voltage or charge amplifier
- Gain determination via numerical integration of single dar or low light pulses

$$G = \frac{1}{R_{load} \cdot G_{Amp} \cdot e} \cdot \int U dt$$

50 Ω

Measured int for a single pulse

Alternatively:

- Gain determination via I_{dark} and DCR pulse frequency
- Method requires corrections for correlated noise

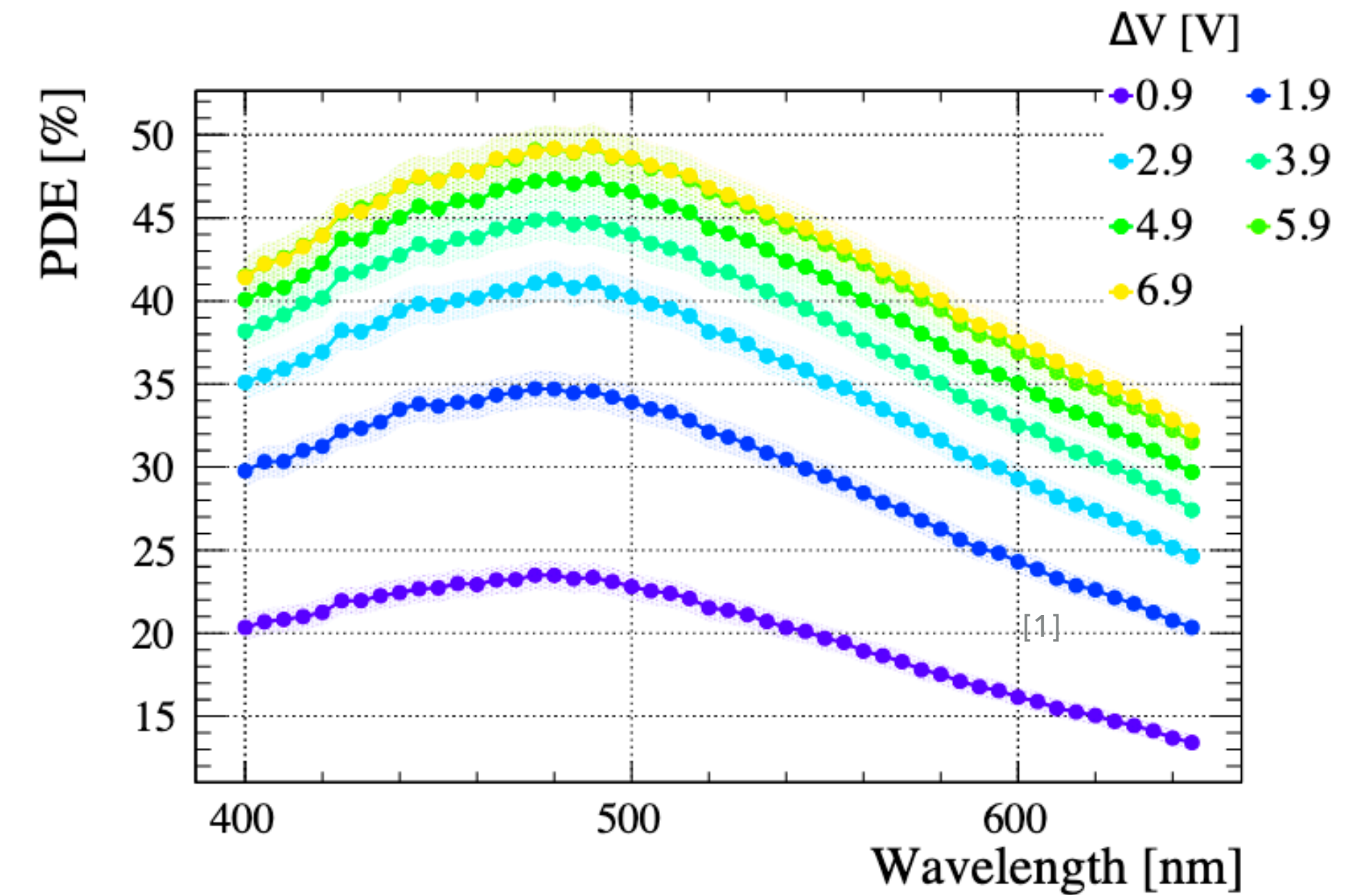
$$I_{dark} = DCR \cdot G \cdot e$$

● **Photo detection efficiency (PDE):**

$$PDE = \frac{\#\gamma_{det}}{\#\gamma_{inc}} = QE \cdot \epsilon_{geo} \cdot P_{01}$$

Quantum efficiency
AV probability
Fillfactor

- ▶ Measured as a function of λ and ΔV



● **The created charge from AV divided by the electron charge defines the gain:**

- ▶ Detector is a capacitor : $Q = C \cdot \Delta V$
- ▶ Larger pixels have a higher capacity and therefore, higher gain
- ▶ Typical values for a detector with $(50 \mu m)^2$ pixels: $10^6 e/ph \cdot 10^7 e/ph$

$$(\Delta V = 1 - 7V) \quad [1]$$

● Determination of V_{BD} :

➔ V_{BD} is obtained via a linear fit

$$\left[\frac{d \ln(I)}{dV_{bias}} \right]^{-1} = I \cdot \left[\frac{dI}{dV_{bias}} \right]^{-1} = \frac{V_{bias} - V_{BD}}{\epsilon} \sim \Delta V$$

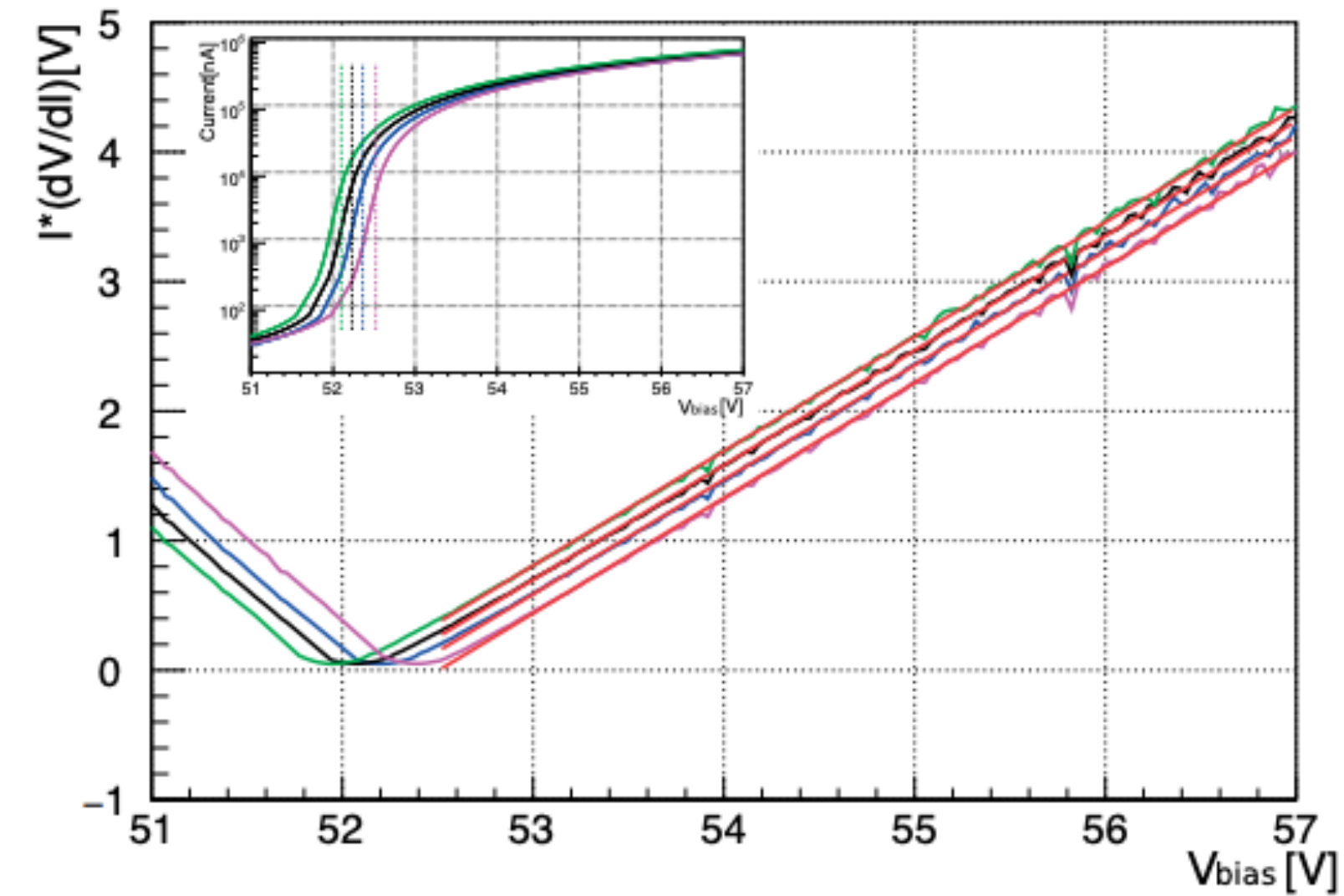
● Measurement of R_Q :

➔ IV scan in forward direction

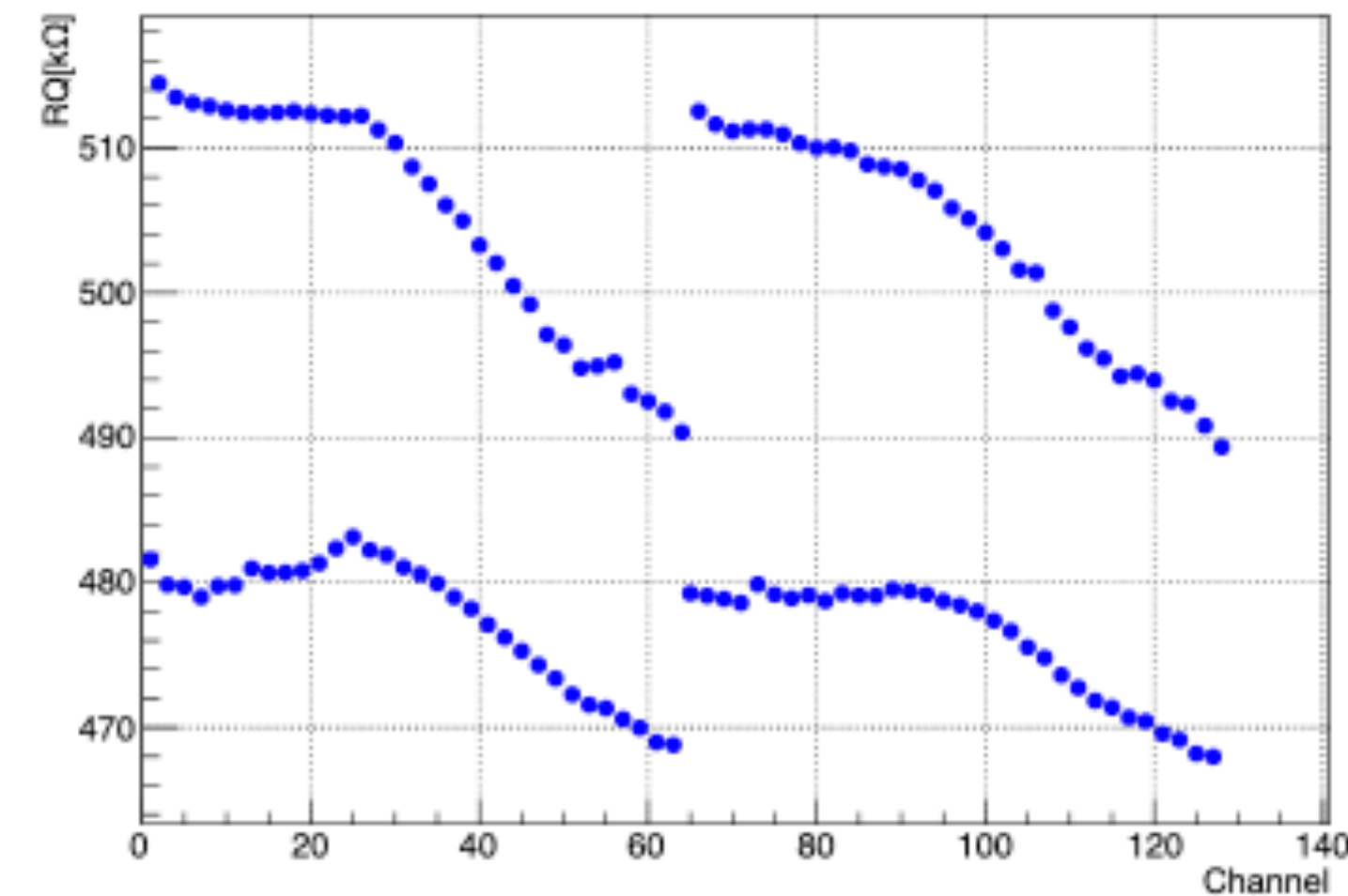
➔ Linear fit in $\Delta V \subseteq [-3.5, -1] \text{ V}$

$$R_Q = N_{pixels} \cdot (dV/dI)$$

$$R_Q \sim 470 - 570 \Omega$$

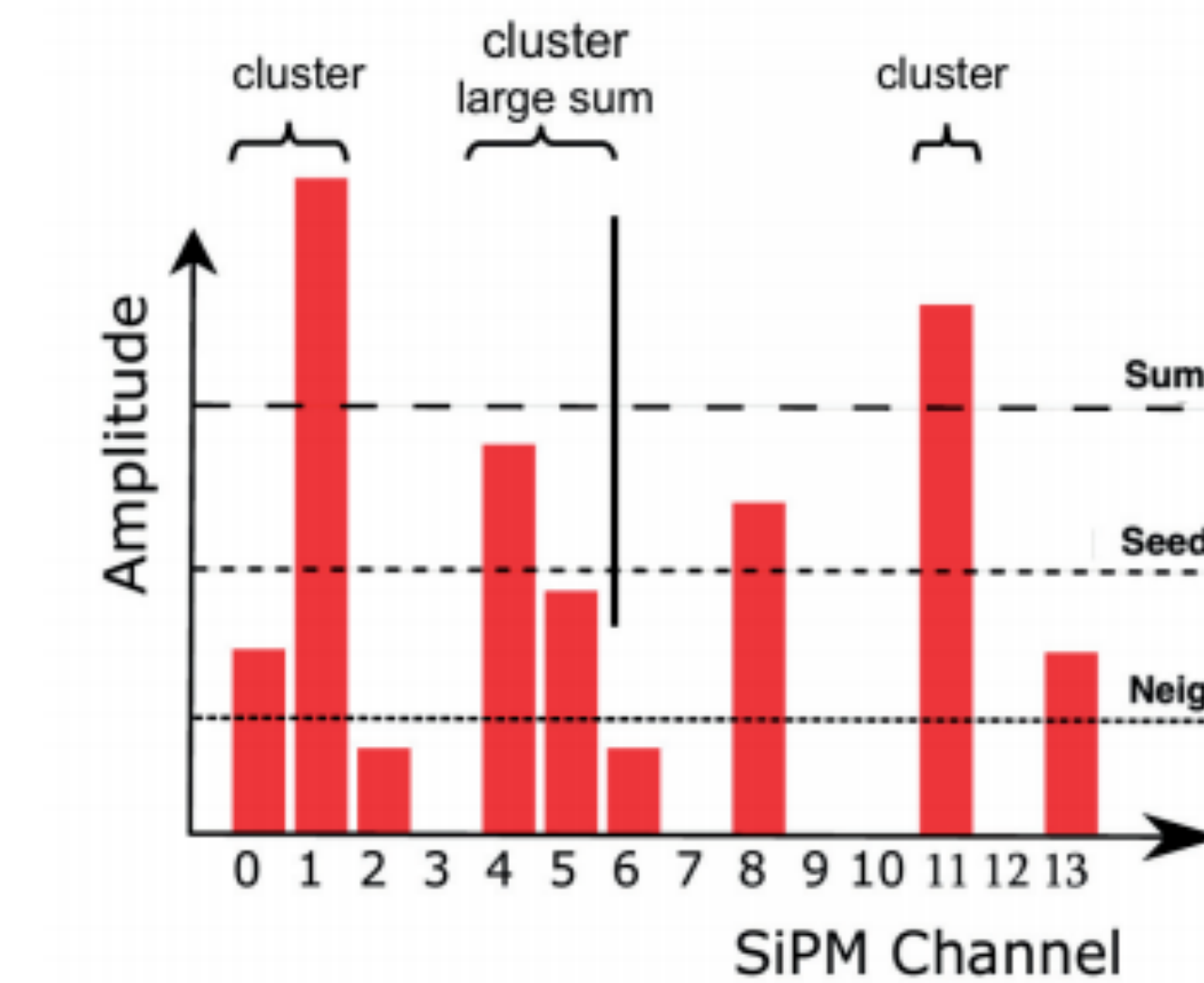


[A. KUONEN, EPFL_TH8842.pdf]



● **Light yield measurement with a short fiber module:**

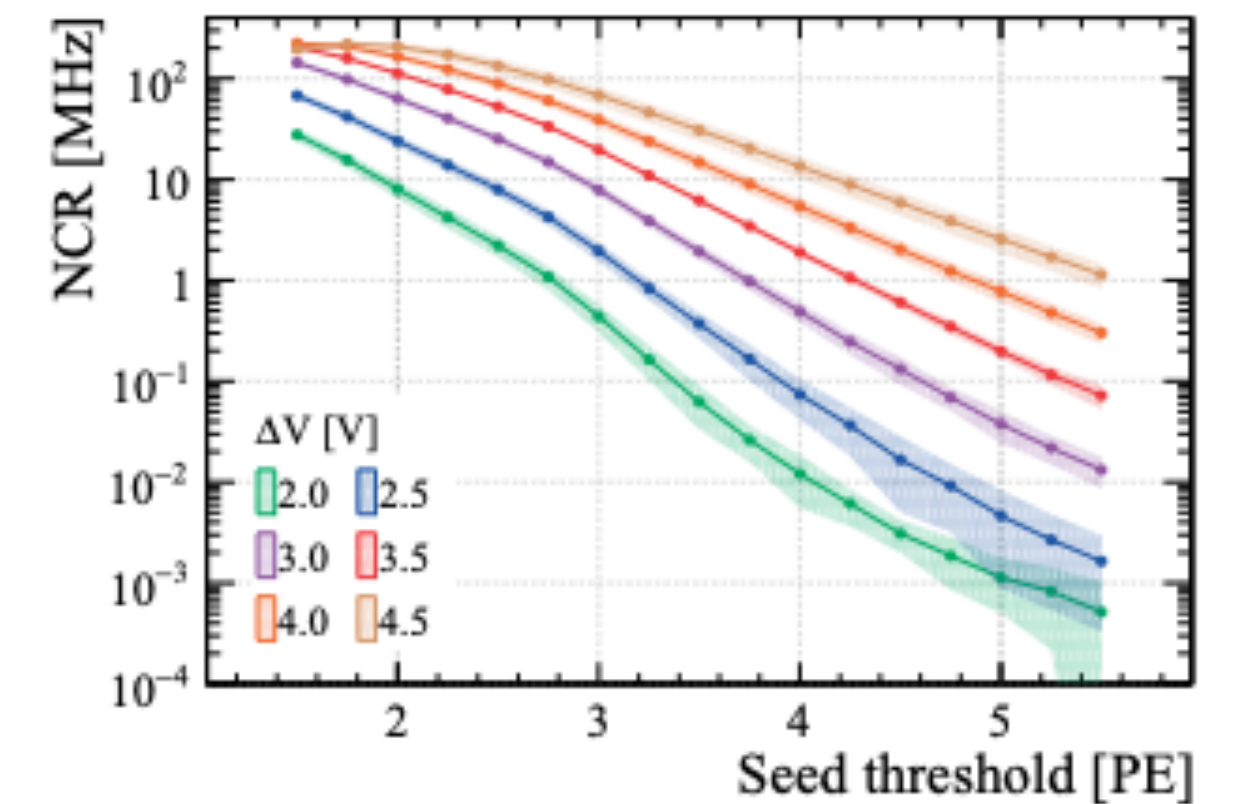
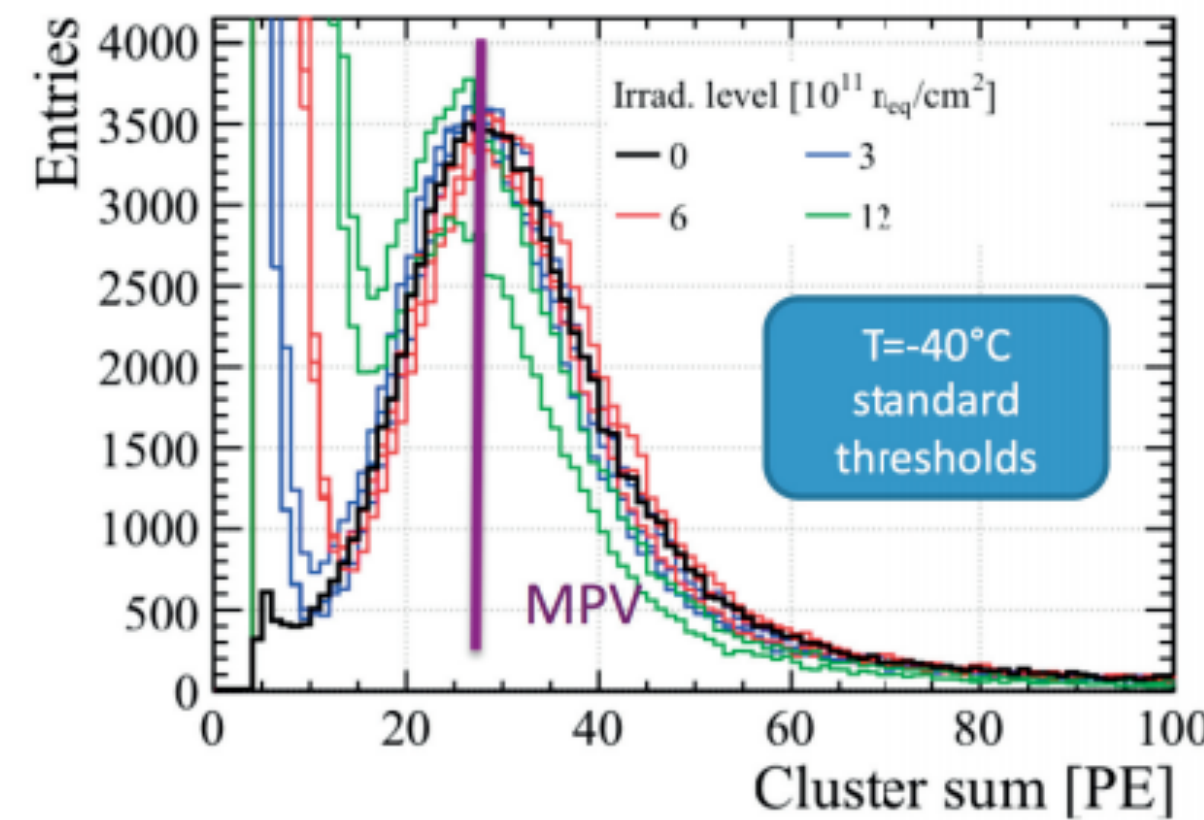
- ▶ Inject e- into fiber module (34 cm)
- ▶ 10-bit clustering algorithm
- ▶ Light yield is the most probable value of the cluster sum for a MIP
- ▶ Corrections for DCR



<KUONEN,EPFL_TH8842.pdf>

● **Noise cluster rate (NCR):**

- ▶ Produced by correlate
- ▶ Random overlap dark pulses

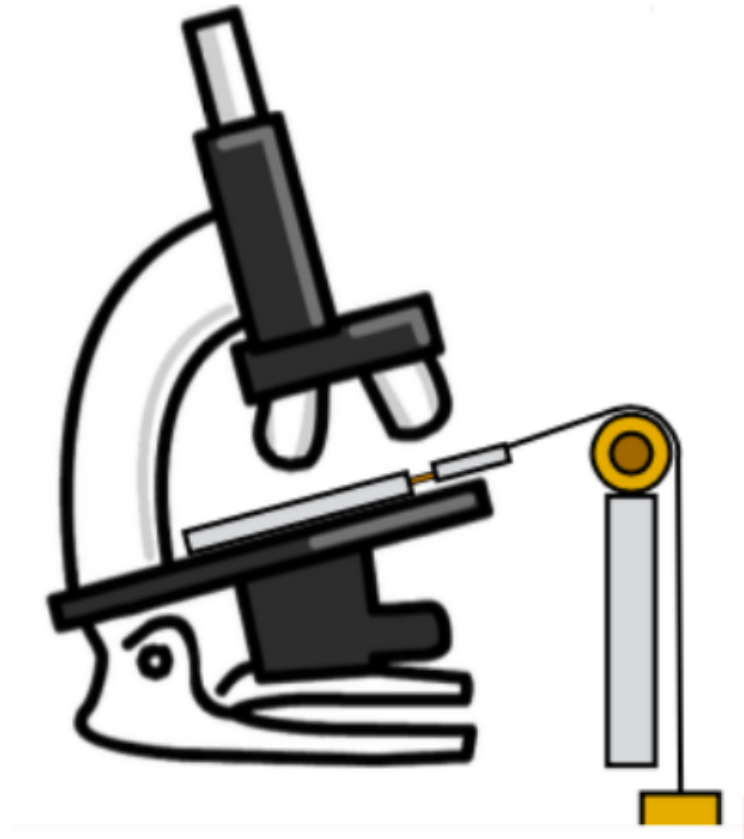
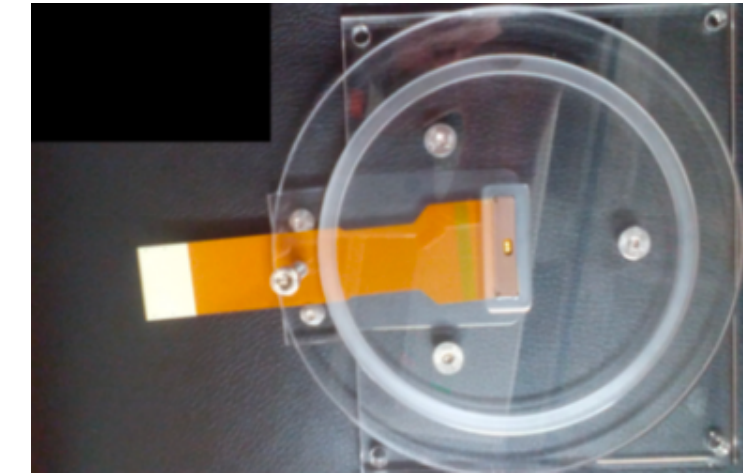


$$f_{NCR} = \frac{N_{NC}}{N_{ev}} \cdot 40\text{MHz}$$

[A. KUONEN,EPFL_TH8842.pdf]

◎ **Gluing tests:**

- ▶ No failures under 7h with 3kg
- ▶ No failures under peak traction <10 kg



◎ **Thermal chamber test (ageing):**

- ▶ 100 cycles -55 to 100 °C (= 10 years)
- ▶ Electrical tests
- ➔ No failures



8 detectors irradiated in Ljubljana (Slovenia):

- ▶ Neutrons with 3, 6 and $12 \cdot 10^{11} \text{MeVn}_{eq}/\text{cm}^2$
- ▶ 4 days of annealing at 40°C
- ▶ DCR measurement:
 - ➔ 15 MHz at -40°C after $6 \cdot 10^{11} \text{MeVn}_{eq}/\text{cm}^2$
 - ➔ Batch 1: 12 MHz

